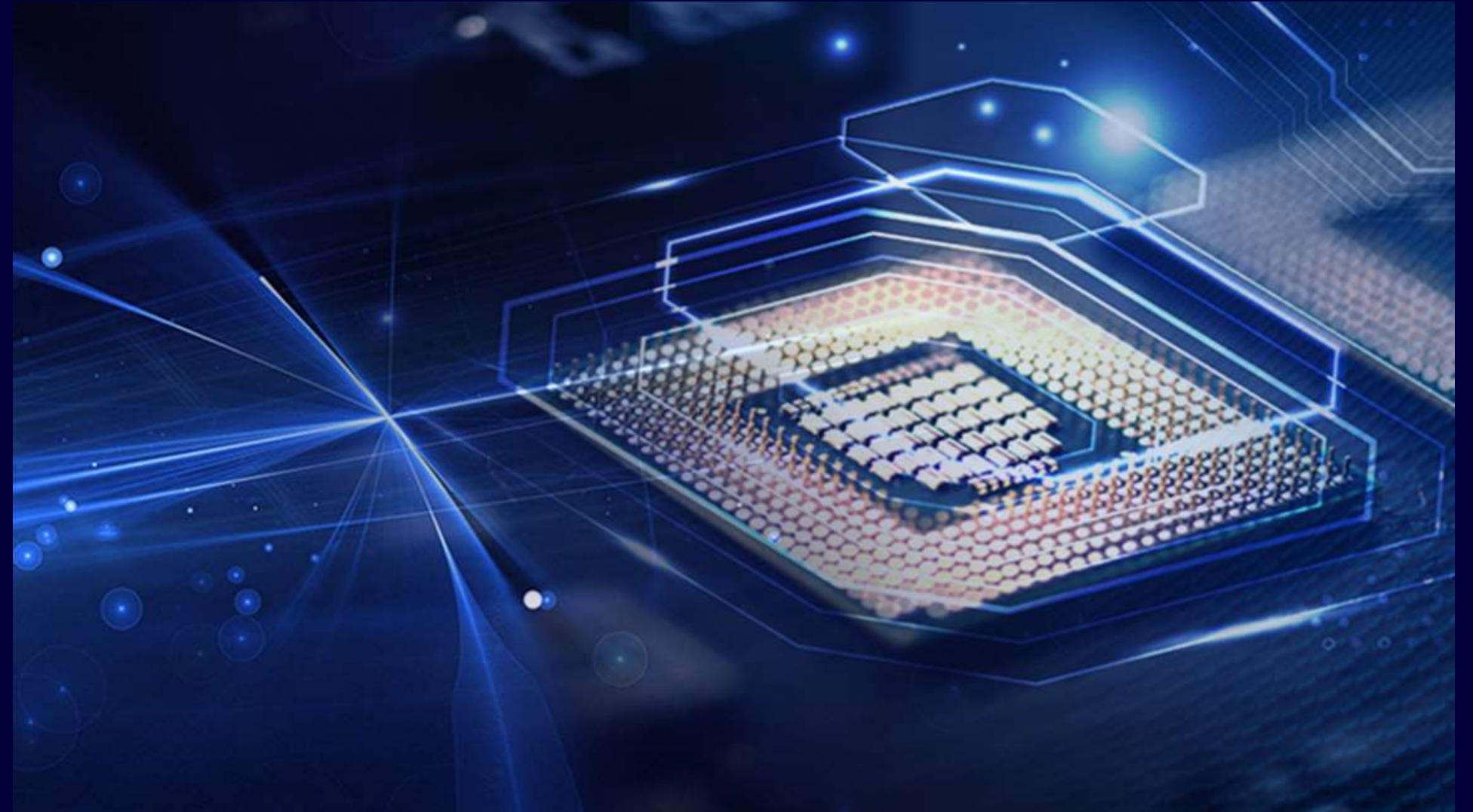


ALTER

ALTER FRANCE

Inspired by Knowledge



TÜV NORD Group

Figures, data, facts

The TÜV NORD GROUP at a glance (2022's figures)

ALTER



1,451.8

Million Euro sales



12.238

Employees worldwide

TÜVNORDGROUP
TÜVNORD · DMT · ALTER · TÜVIT

4

Core Brands

in the Industrial Services, Mobility, Training,
Engineering and Natural Resources, Aerospace
and IT business units



100

Active in 100 countries



82

Group Companies

TÜV NORD Group

ALTER

Taken together, this is our expertise for your success.

Below Ground



On Ground



In space



With our knowledge, we stand for safety, independence and quality – everywhere and at all times. We look to the future and dedicate ourselves to making our clients even more successful in the connected world.

We protect lives, goods and natural resources. We achieve this by offering services in testing, inspection, certification, engineering and training.



ALTER Group

ALTER Group is a leading engineering company which provides reliable and agile solutions in engineering, procurement, **assembly, and test to many of the world's** most innovative technologies, such as semiconductors, electronic equipment and geospatial intelligence.

Our company is present in space, aeronautics, nuclear, automotive, medical and defence among many others.

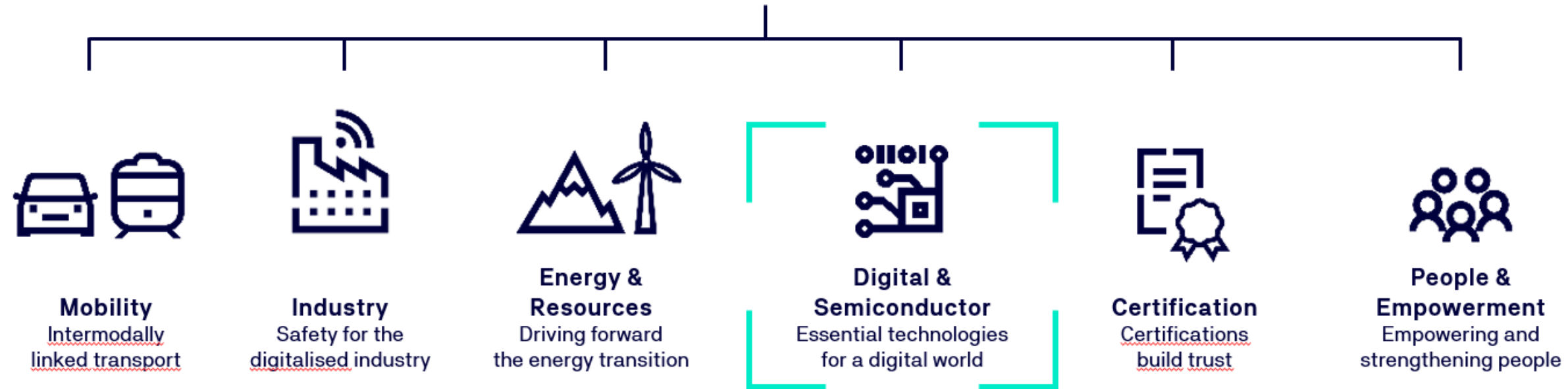
ALTER



ALTER Group

Figures, data, facts

TÜVNORDGROUP



ALTER

ALTER Group

Figures, data, facts

NOVA

New Business Unit : Digital & Semiconductor



82

Million Euros Revenues



7

sites



470

Employees



>8500

M2 laboratories



36

Years in the market

ALTER

ALTER France

ALTER France at a glance

ALTER



12

Millions euros Revenues



10%

of Revenues
Invest



59

Employees



1600

M2 Laboratories



Alter France Qualification

ALTER

- UNE-EN 9100:2018 (QM for Aerospace & Defense)
- UNE-EN-ISO 9001:2015 (QM Requirements)
- UNE-EN-ISO 14001:2015 (Environmental management systems)
- ISO 45001: 2018 (Health & Safety Management System)
- CNES SME Label (French industry base through their
 - Cutting-edge expertise,
 - Impressive ability to innovate,
 - Great agility



- French Fab SME Label



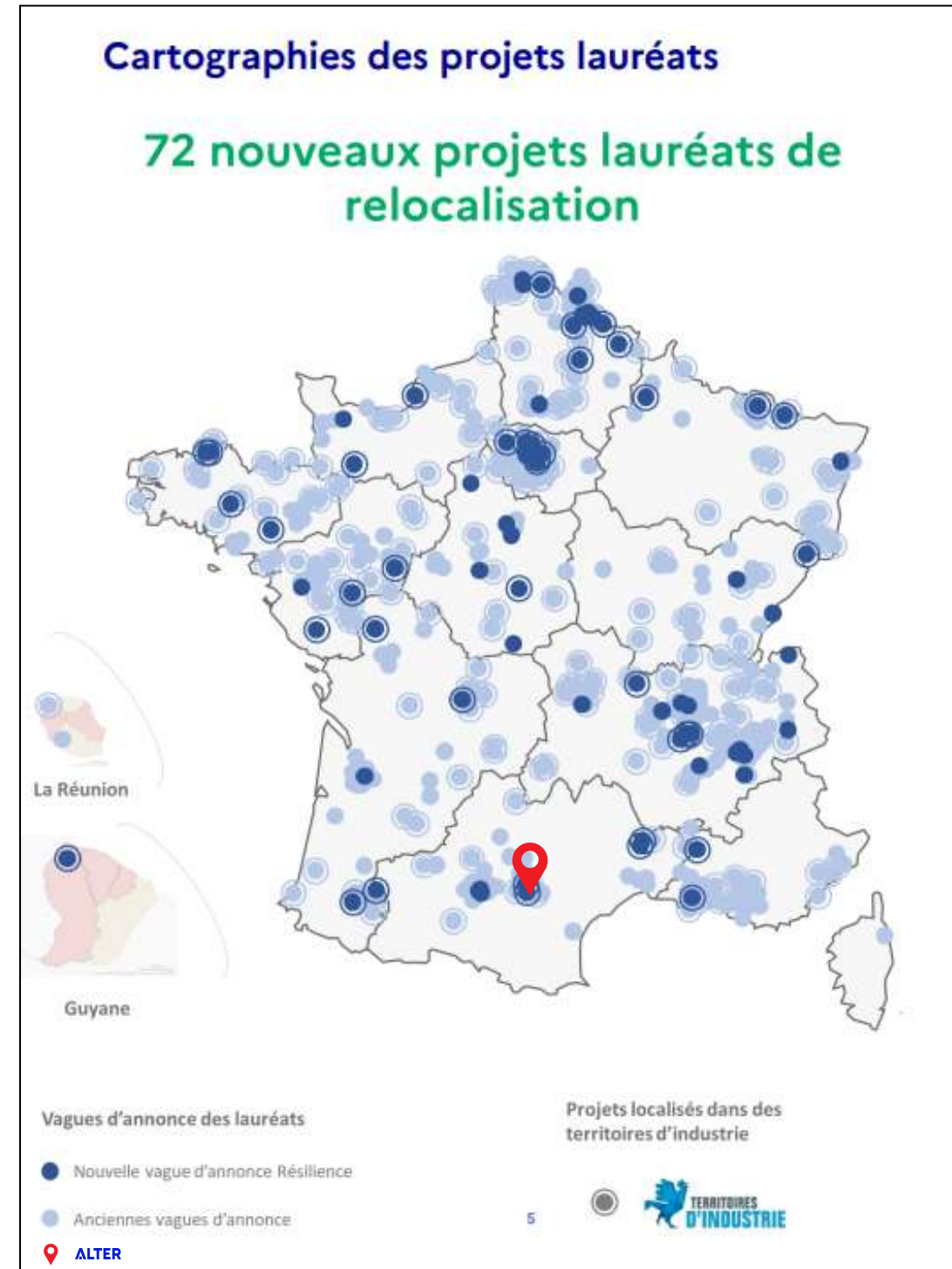
Alter France Investment



GOUVERNEMENT
Liberté
Égalité
Fraternité

re localiser

17 février 2022



Projet « TEST COMPOSANTS ELEC »

ALTER TECHNOLOGY TUV NORD FRANCE – PME

Ramonville-Saint-Agne (31) - Occitanie

Alter Technology est spécialisée dans l'évaluation, la qualification, le test et l'analyse physique et de défaillance des composants électroniques destinés à des applications de très haute fiabilité. L'objectif de son projet est de moderniser les moyens industriels de test des composants électroniques critiques, dont l'entreprise Alter Technology France est un acteur structurant dans la chaîne de valeur (applications Spatiales, Aéronautique, Défense, etc...). Les objectifs sont de pouvoir tester les nouvelles technologies semi-conducteurs dites de rupture tel que le GaN Power ou RF et de gagner en compétitivité et réactivité pour la société et pour les clients français leaders sur leur marché à l'international.

Alter Technology specialises in the evaluation, qualification, testing and physical and failure analysis of electronic components intended for very high reliability applications. The aim of the project is to modernise the industrial test facilities for critical electronic components, for which Alter Technology France is a key player in the value chain (space, aerospace, defence applications, etc.). The objectives are to be able to test new breakthrough semiconductor technologies, such as such as GaN Power or RF, and to improve competitiveness and responsiveness for the company and for French customers who are leaders in their international markets.



Business sectors

ALTER



Domain of Expertise

ALTER



Customers - Space Market

ALTER



KONGSBERG



Customers - Aero / Auto / Indus Market



Company

ALTER is the leading provider of microelectronic and semiconductor services acting as the European OSAT in parts & system engineering, parts procurement, assembly, and testing for aerospace and harsh environment markets.

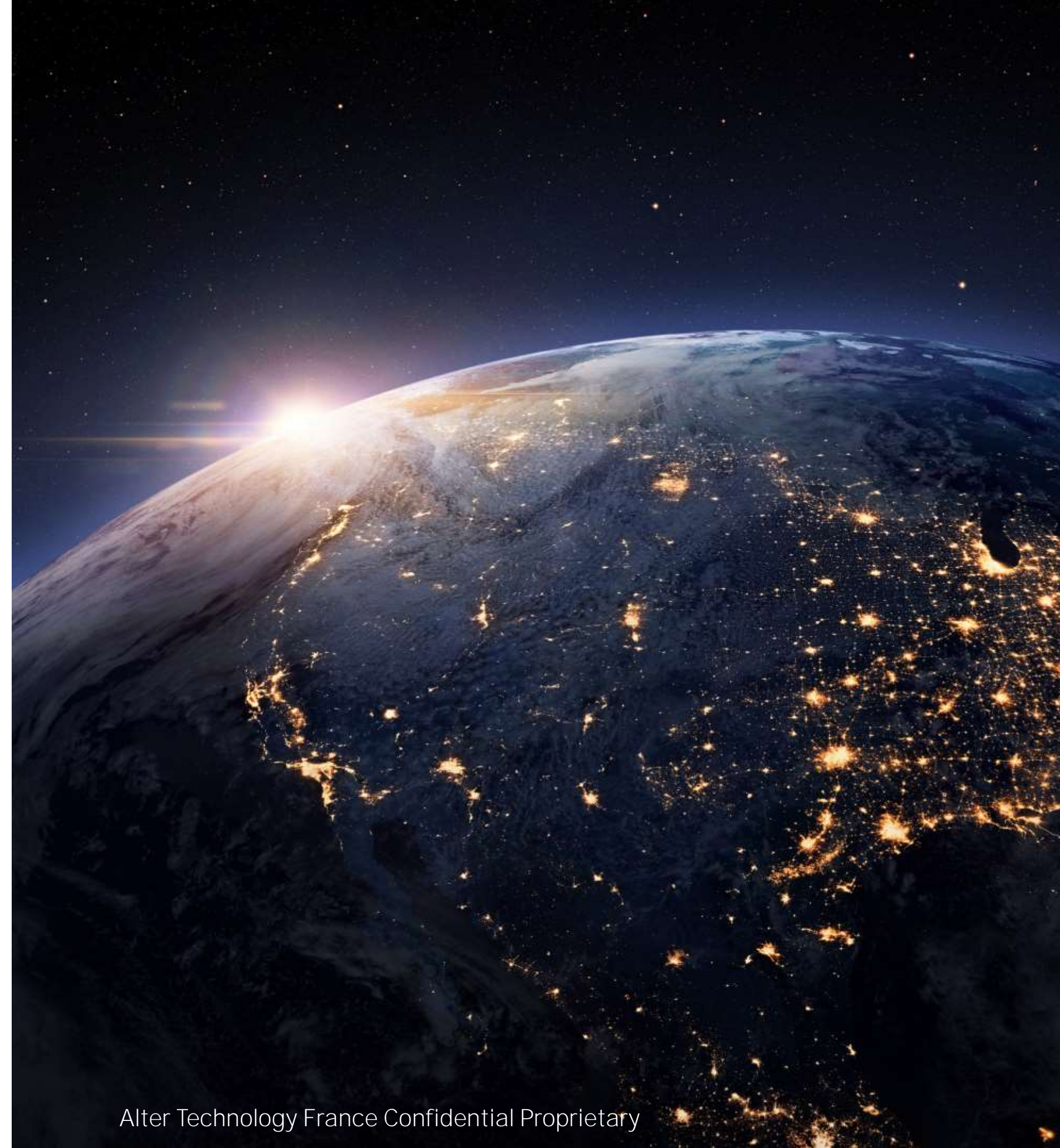
Our company develops and offers complete turn-key solutions covering all the backend engineering tests such as wafer probing, microelectronic and optoelectronic assembly, parts qualification & reliability testing, final testing and technology analysis.



ALTER

Outsourced Semiconductor Assembly & Test

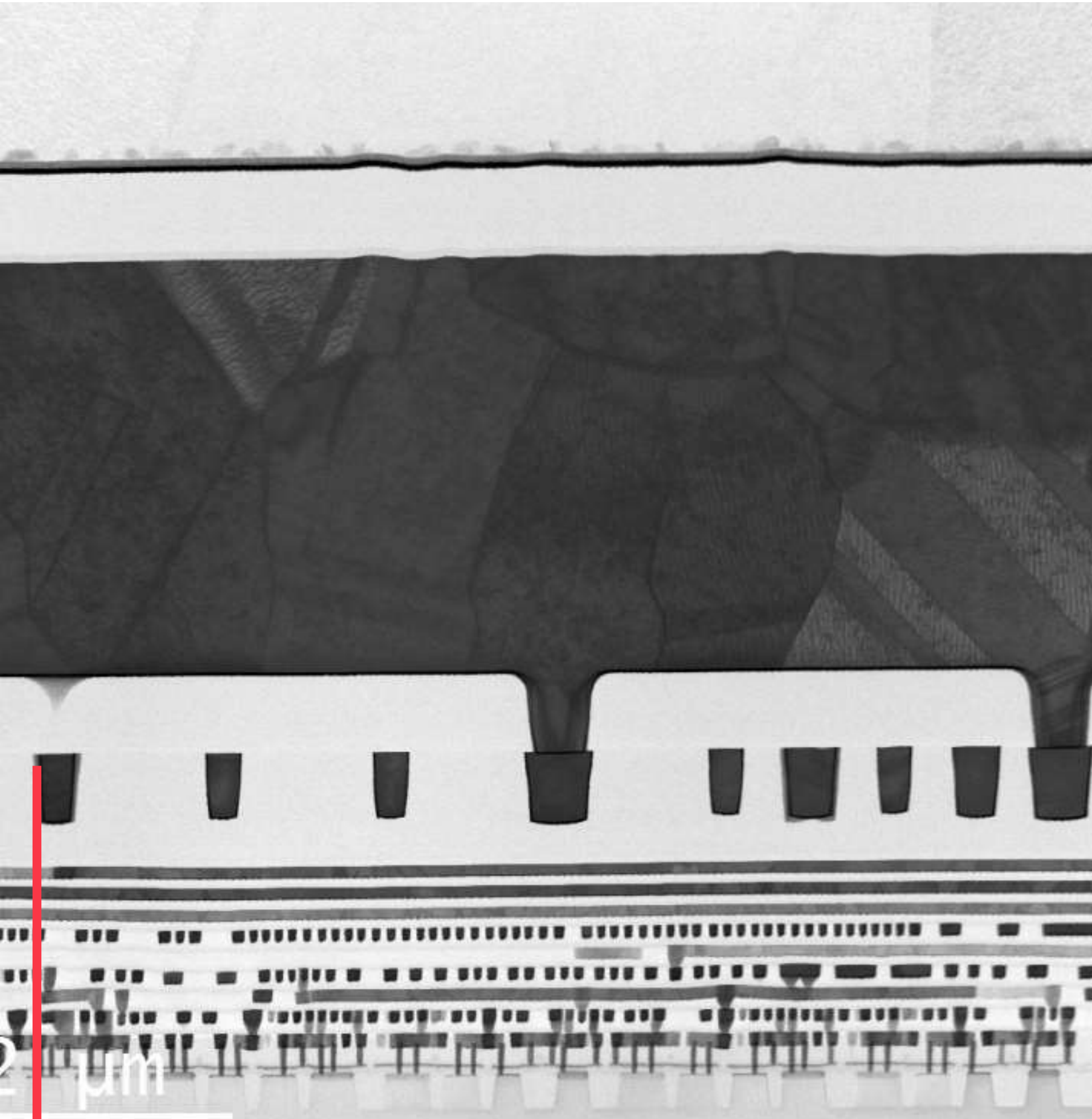
ALTER France ensures efficient chip assembly & packaging, Electrical testing and assists in New Product Introduction (NPI) processes for seamless integration of new semiconductor products for diverse mission profiles and markets.



Technology Analysis

Our Technology Analysis Lab is in charge of performing deep-dive Analysis on product construction or product failure.

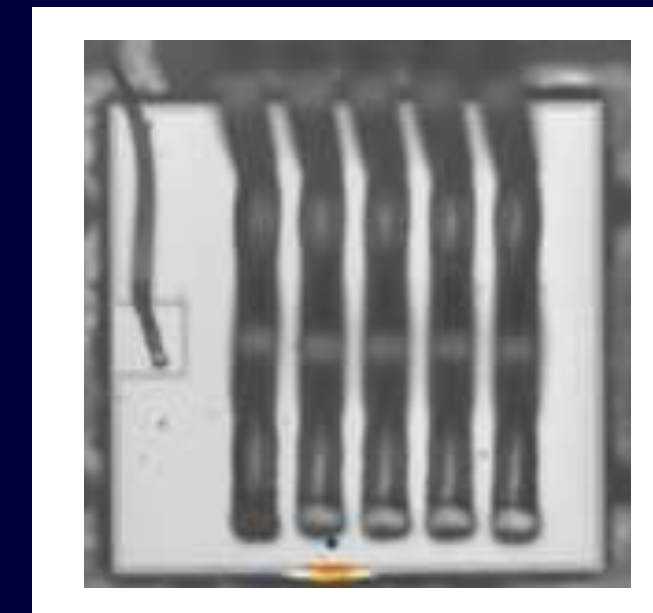
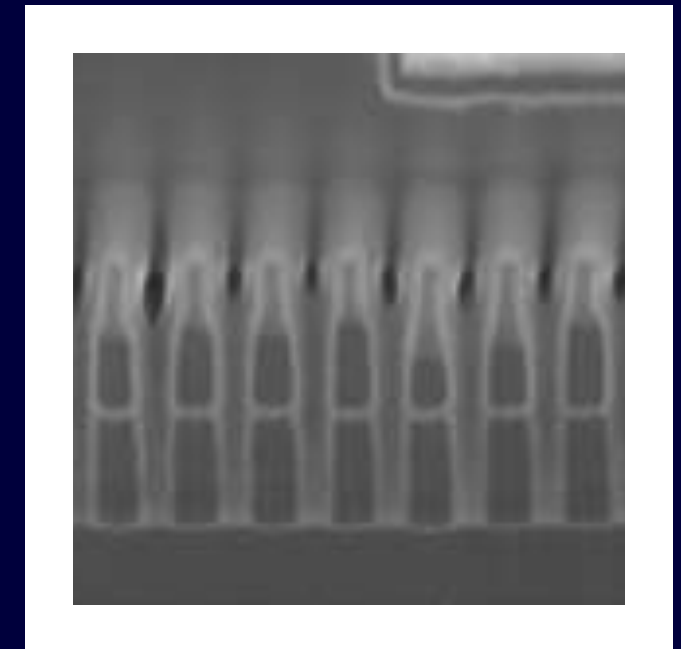
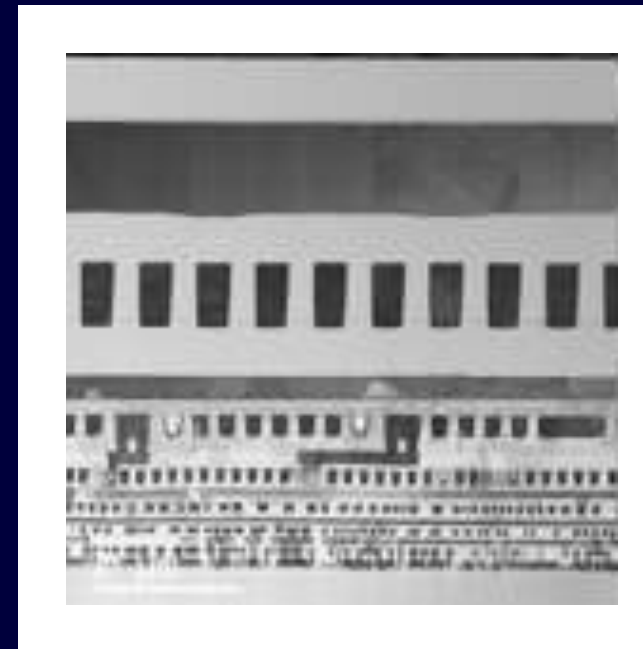
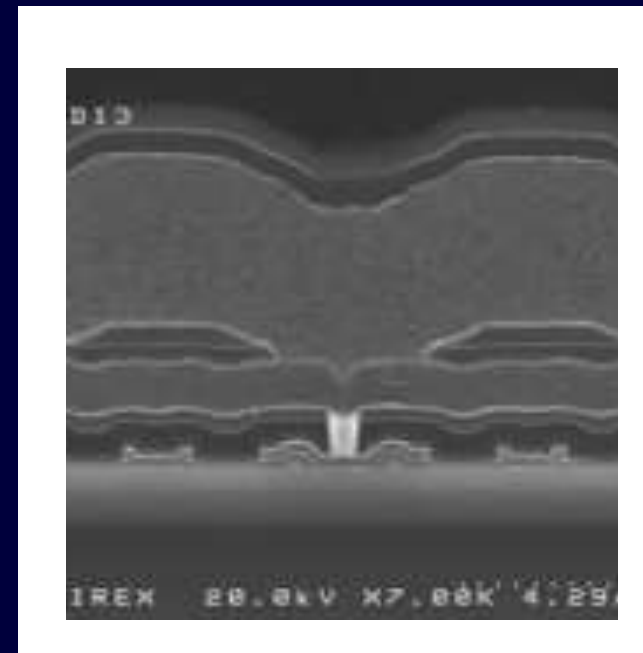
The laboratory mission is to identify potential weakness or root cause of malfunction on part or system.



Technology Analysis

LAT services: Technical expertise with appropriate tools is conducted on product families covering PCB domain to IC area in order to ensure the compliance to the Standards requirement and the State-Of-The-Art quality level.

- Construction analysis
- Reverse analysis
- Destructive Physical analysis
- Failure analysis



LAT Capability and Tools



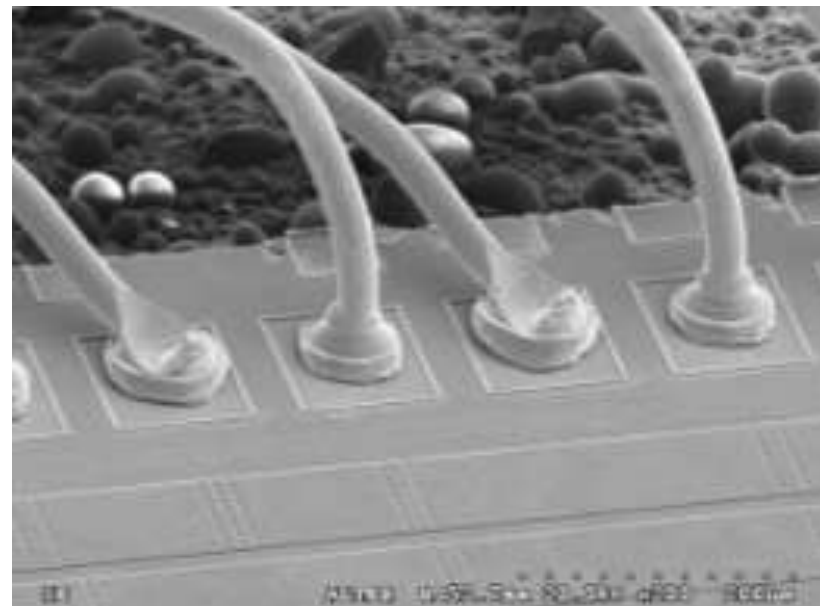
ALTER

Destructive Physical Analysis (DPA)

DPA is routinely used by the aerospace industry in order to qualify electronic components to Class “S”. More and more commercial applications are using DPA screening to dramatically increase the reliability of their products in the field. Higher reliability electronic components are often required to operate for long periods of time. Orbiting satellites are good examples of this situation. Parts that meet the requirements for “space usage” are also used in applications where replacement is difficult and/or failure engenders great risk.

Specifications :

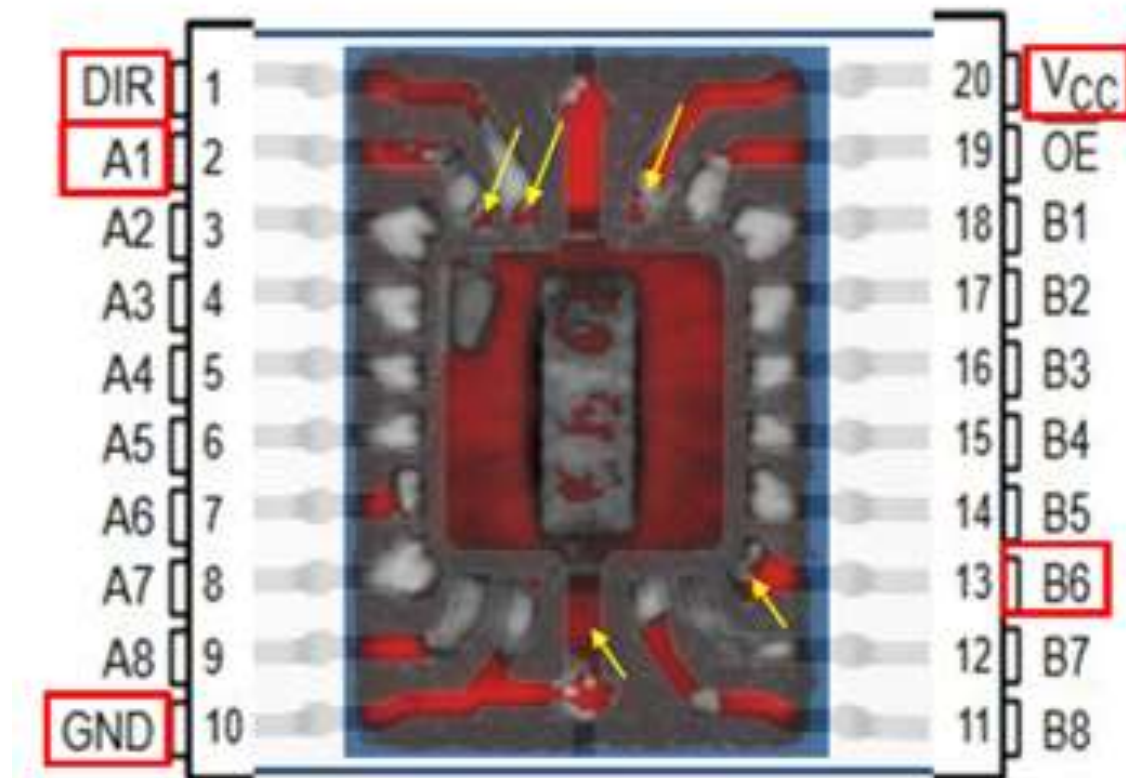
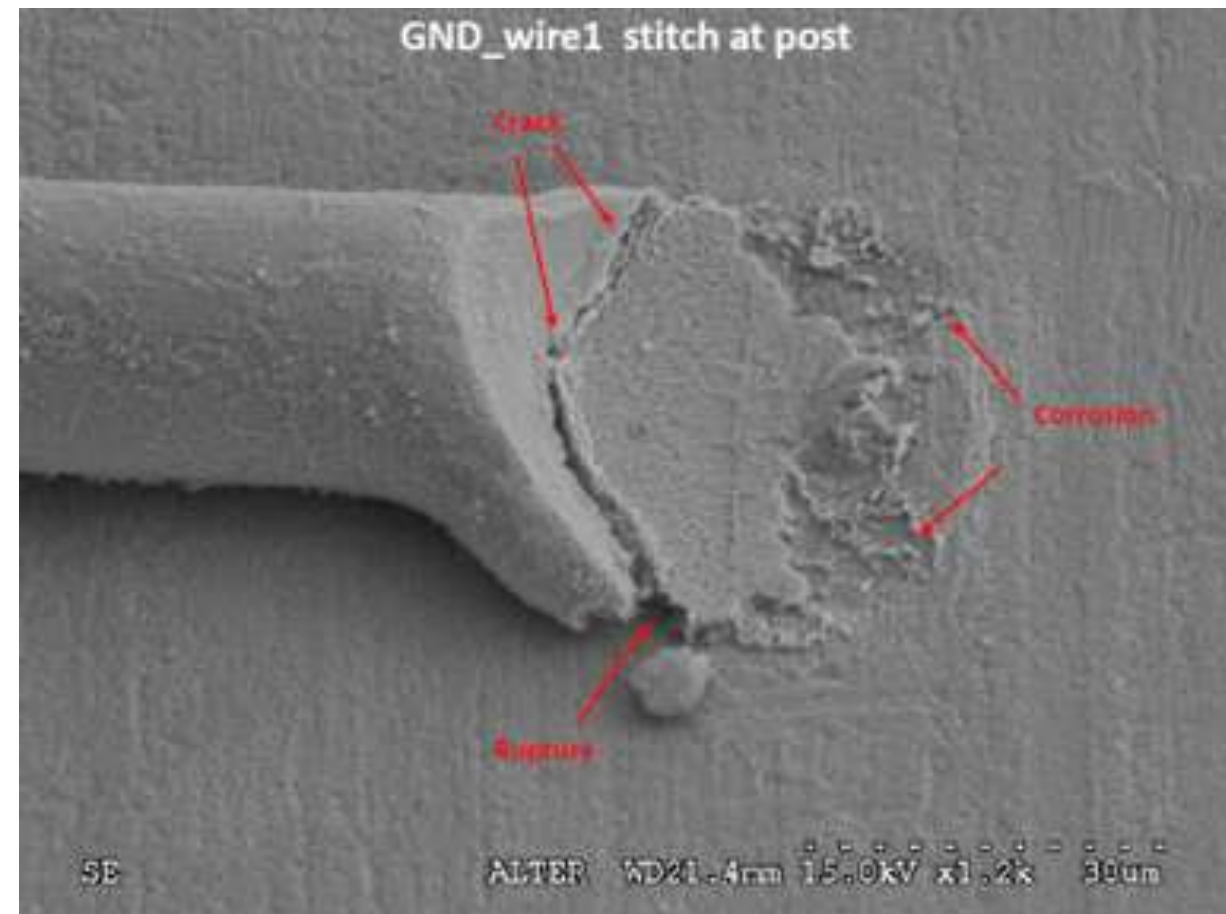
- MIL-STD-1580 MIL-STD-883MIL-STD-750 MIL-STD-202
- SSQ-25000
- ESCC, JEDEC, NASA



Sample Serial Number	1	2	3	4	5
External Visual Inspection	X	X	X	X	X
Radiography	X	X	X	X	X
Acoustic Tomography	X	X	X	X	X
Marking Permanency	X	X	X	X	X
Material analysis	X				
Solderability		X	X		
Terminal Strength		X	X		
Opening	X	X	X	X	
Internal Visual Inspection	X	X	X		
SEM inspection I		X	X		
Bond Shear		X	X	X	
SEM inspection II			X	X	
Glassivation Integrity	X	X			
Bond Cratering	X	X			
Package Cross Section					X

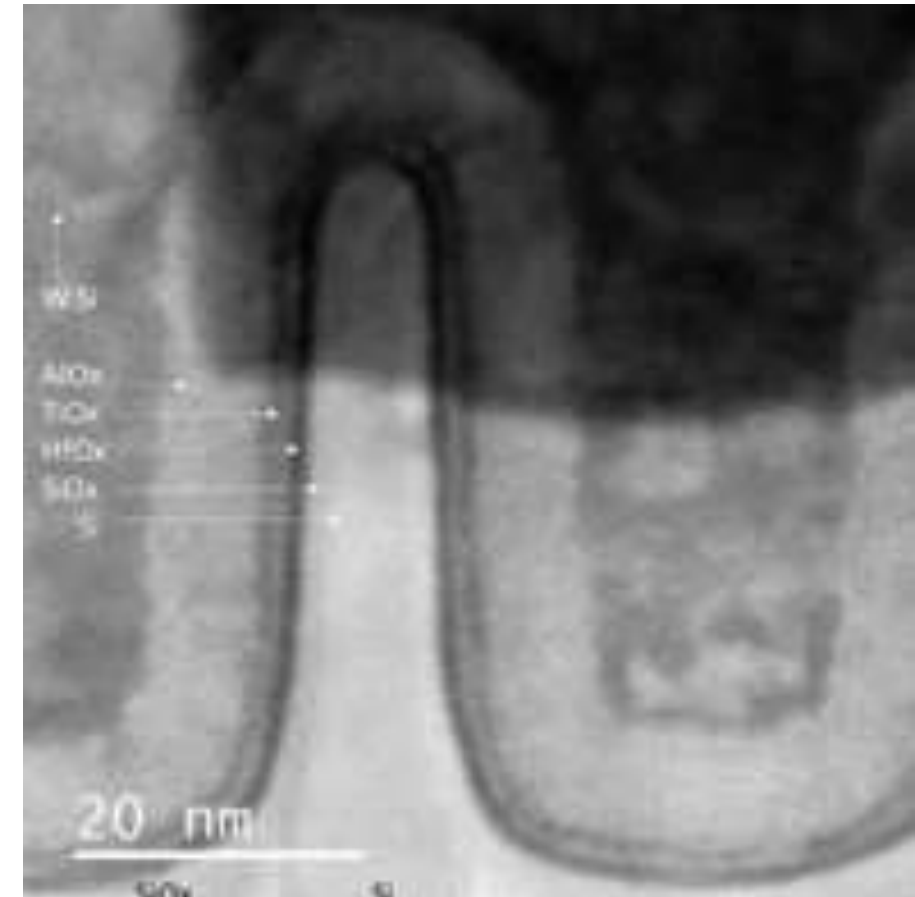
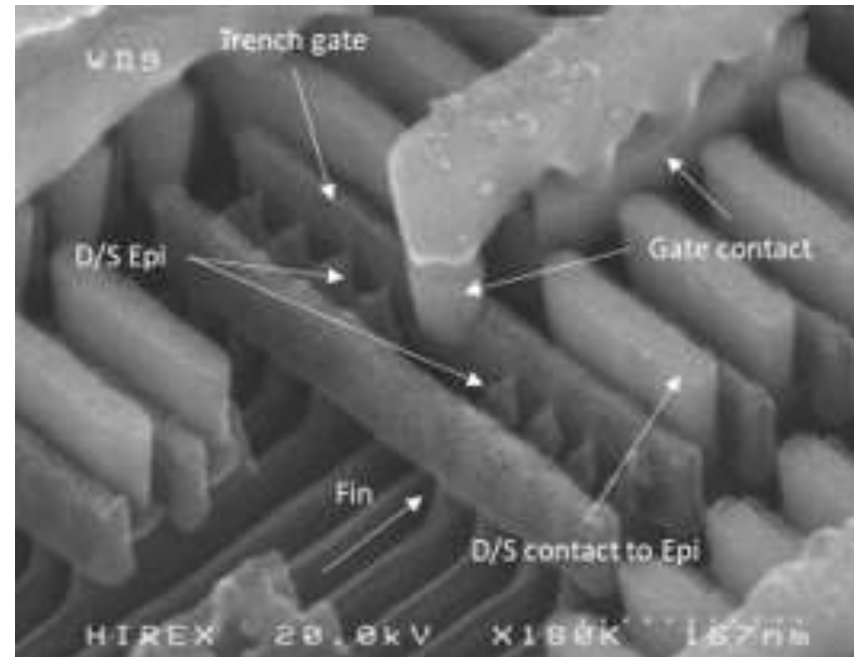
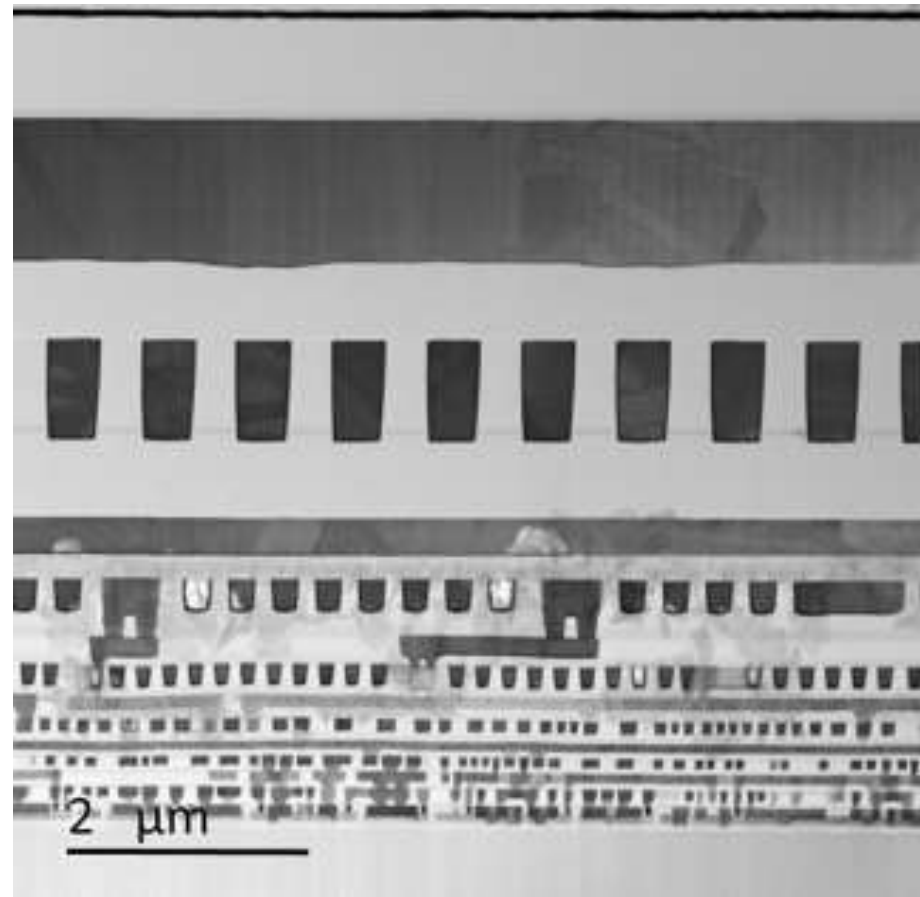
Failure Analysis (FA)

From non-destructing analysis to deep-dive physical analysis, our failure analysis approach answers to our customer with just-in-time commitment and technical demonstrations.



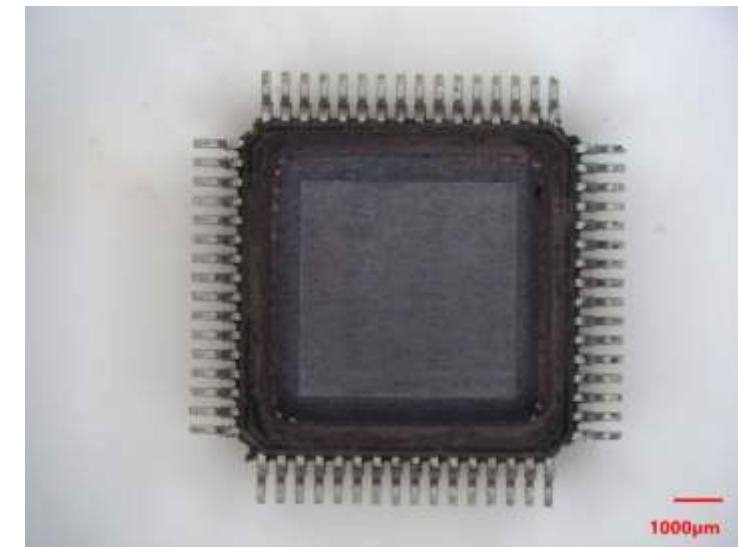
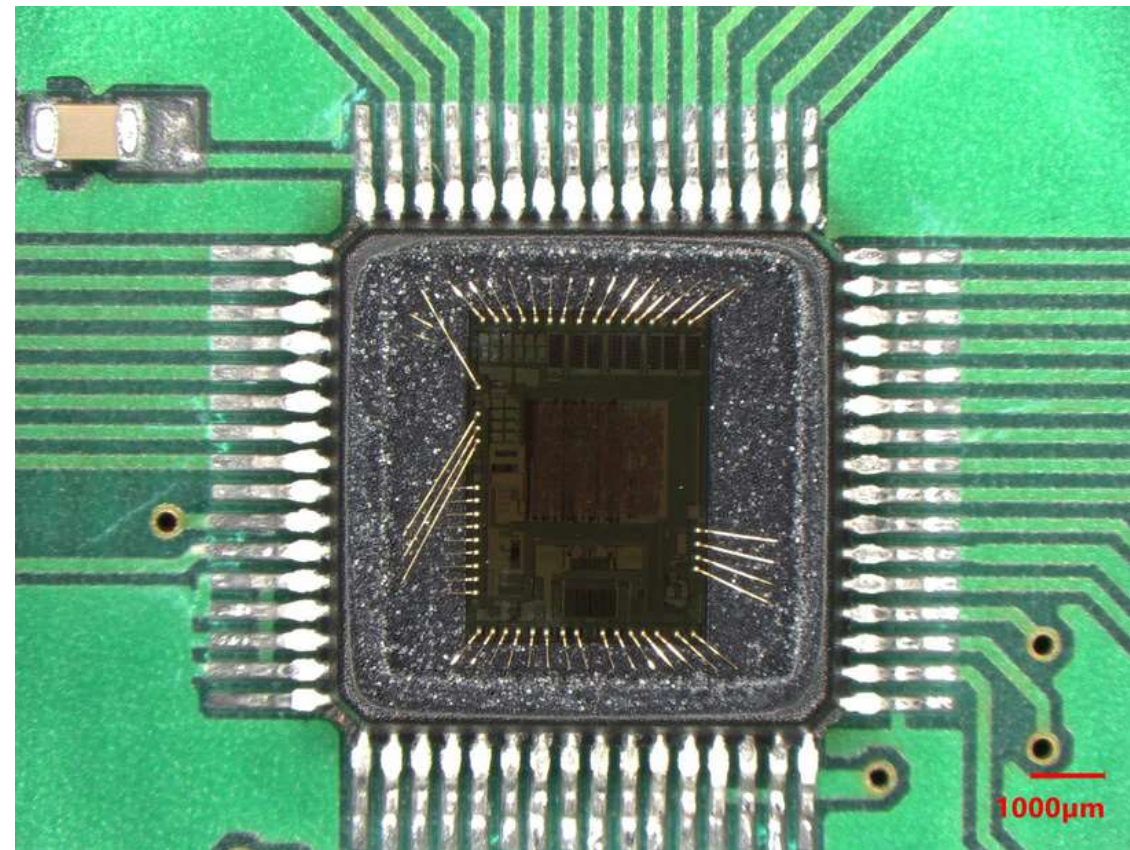
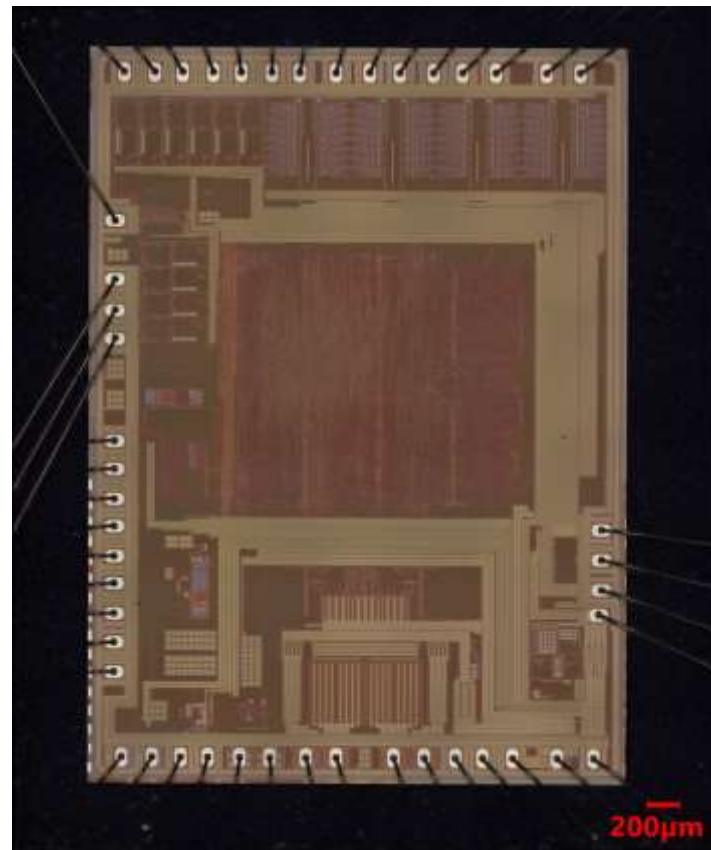
Reverse Construction Analysis

Deep dive characterization of FEOL and BEOL on XILINX ZYNQ 16nm Fin FET technology



Sample Preparation

Sample preparation for radiation test with backside thinning or front side access on isolated part and on part-on-board. All specific requests are covered with innovative solutions.



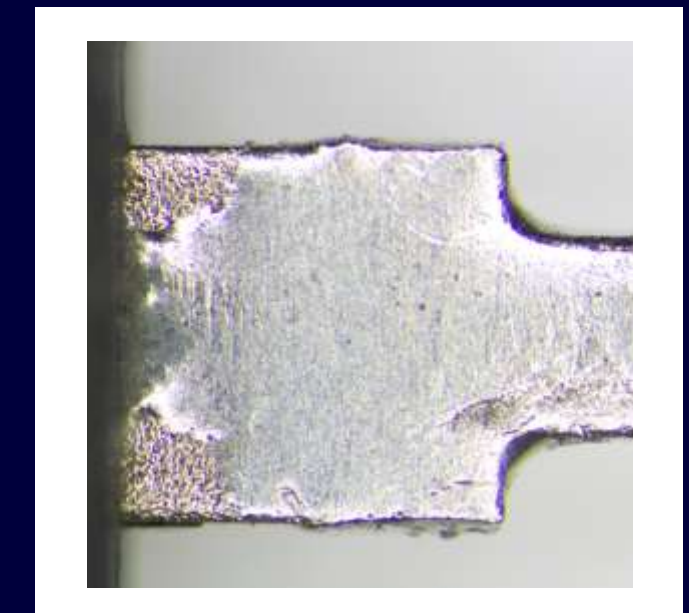
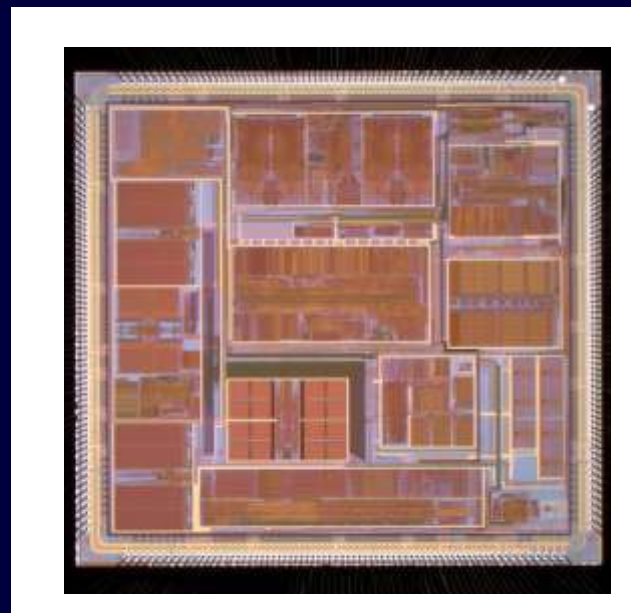
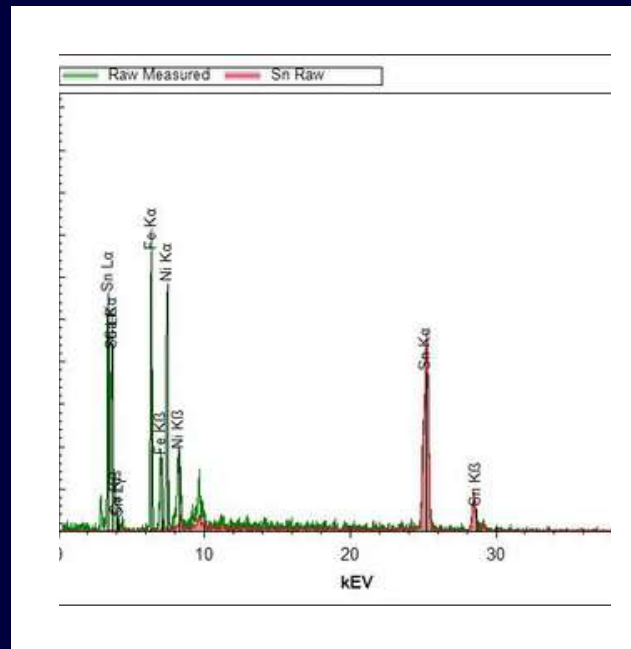
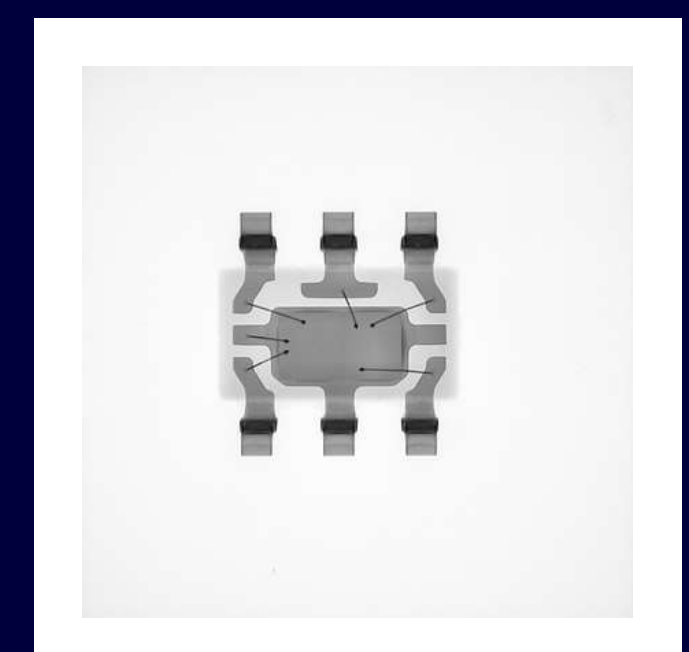
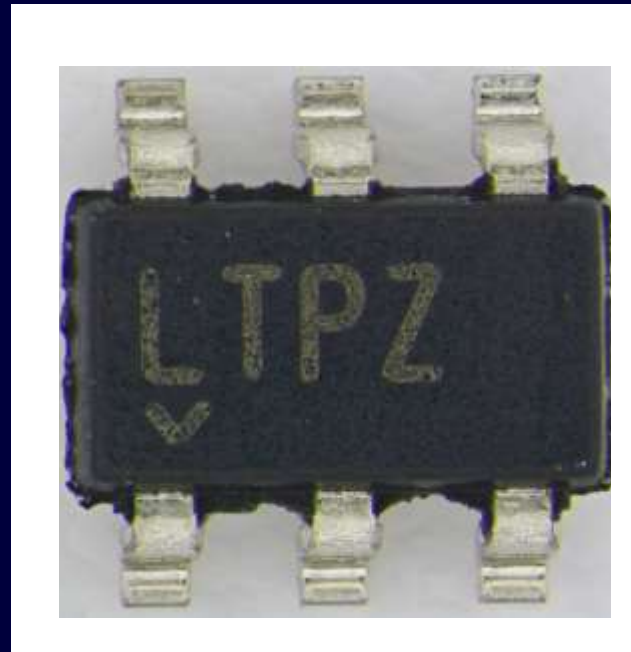
Counterfeit

Alter Technology France provides a full suite of counterfeit semiconductor detection methods to assist our customer in making a determination regarding IC authenticity.

Authenticity detection can be performed according to **company's specifications** or based to industry standards such as SAE A6081, SAE AS5553 and IDEA-STD-1010B.

- External Visual Inspection
- Physical Dimension
- Marking Permanency
- X-Ray
- Environmental and Temperature Testing
- Internal Visual (De-cap)
- OEM Date Code Verification
- XRF Analysis
- Blacktop Test
- Burn-in/Qualification
- Solderability Testing

ALTER



PCB and PCBA Monitoring

Alter Technology France performs a continuous monitoring of PCB/PCBA process quality by cross sectioning of samples.

Applicable Specifications :

- IPC A 610 and IPC A 600
- ECSS-Q-ST-70-08C, ECSS-Q-ST-70-38C, ECSS-Q-ST-70-61C, ...
- Customer specification

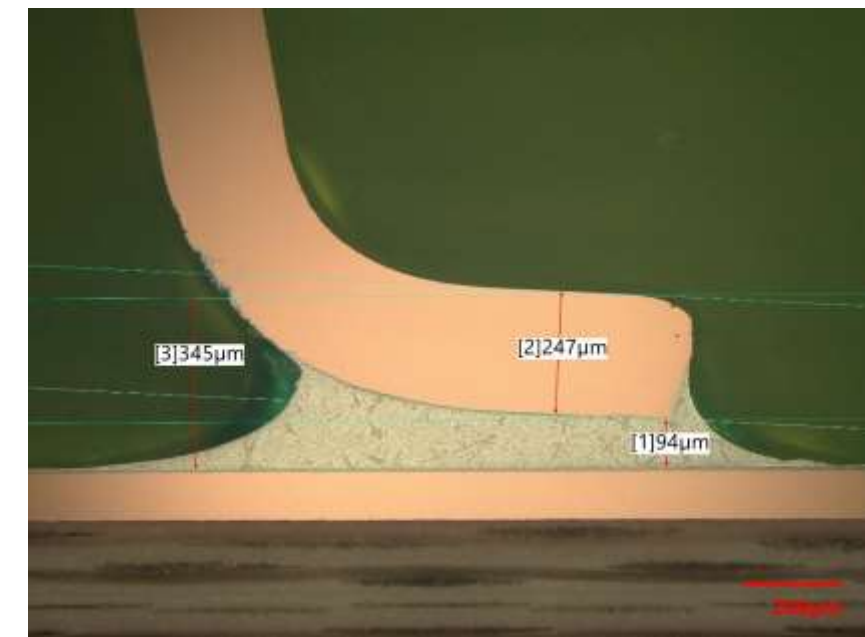
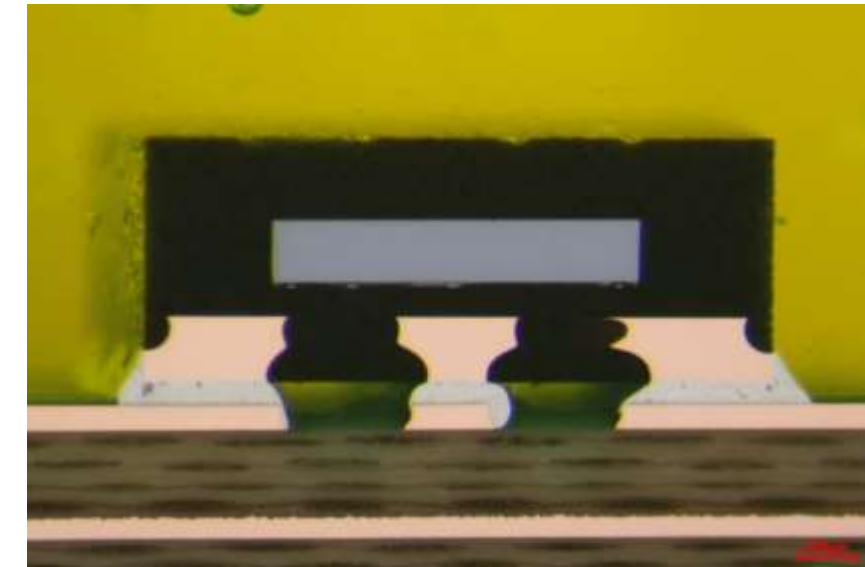
Lab capacity :

- 100 samples per week
- Three automatic polishers multi-sample
- Repeatable process
- Trained operators

Real time reporting :

- SharePoint on common cloud
- Virtual Lab cloud at Alter Technology

ALTER





Total semiconductor testing

Acting as an NPI (New product introduction) facility offering semiconductor Electrical testing, components qualification & characterization.

Alter Technology France's electrical test services encompass both final test and probe. Certifying the semi-conductor product against their applications.

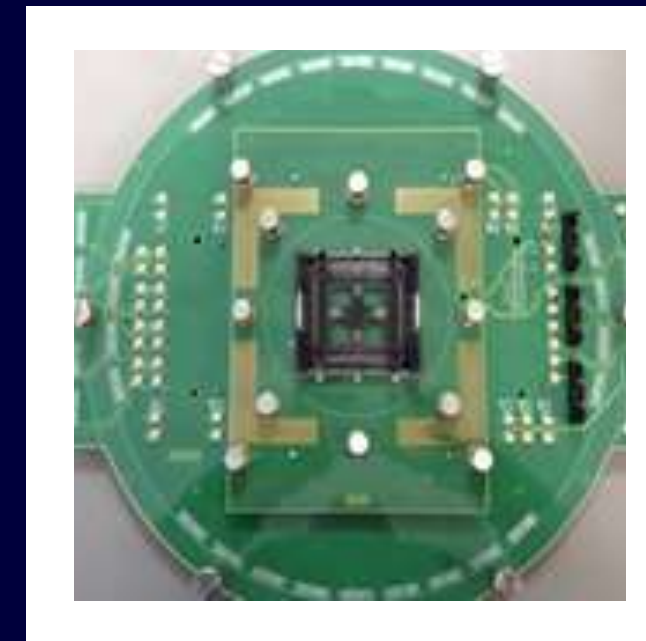
One Stop-shop

Total semiconductor testing

- Electrical testing in temperature -90°C up to +300°C
- Wafer Electrical Testing (Probe) in temperature -40°C up to +200°C
- Reliability tests
 - Burn-In,
 - HTOL,
 - HTRB/HTGB,
 - IOL,
 - ELFR,
 - HAST,
 - THB etc.
- Mechanical & Environmental testing
 - Mechanical shock
 - Vibration (Sinus & Random)
 - Acceleration
 - Salt Spray
 - Temperature Cycling
 - Temperature shock
 - Extreme Temperature cycling -185°C up to +310°C
 - Thermal Vacuum
- FPGA & Programmable component Programming
 - Support all programmable logic families - FPGA, CPLD, PLD, etc.
 - Support all programmable logic manufacturers - Xilinx,
 - Intel/Altera, Actel/Microsemi, Lattice
 - Pin counts to 1000+
- Total dose COBALT 60 (TID) radiation and TNID (Displacement Damage)

ALTER

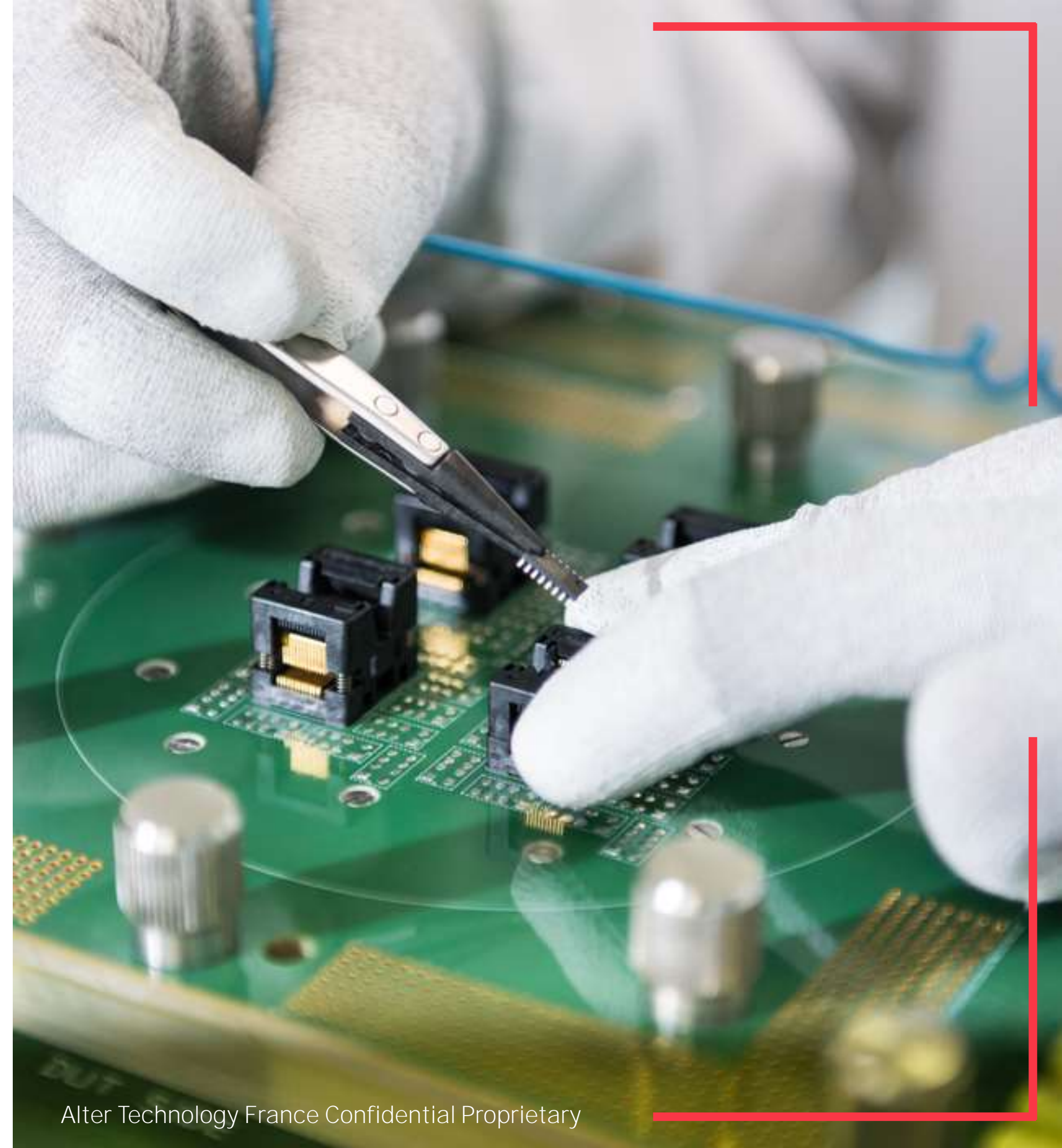
Alter Technology France Confidential Proprietary



Wafer & Parts Testing

- 1 Electrical testing die, Wafer, Package & Module
- 2 Physical and Mechanical Testing
- 3 Electrical testing die, wafer, package & module

ALTER



Wafer & Parts Testing

1 Probers

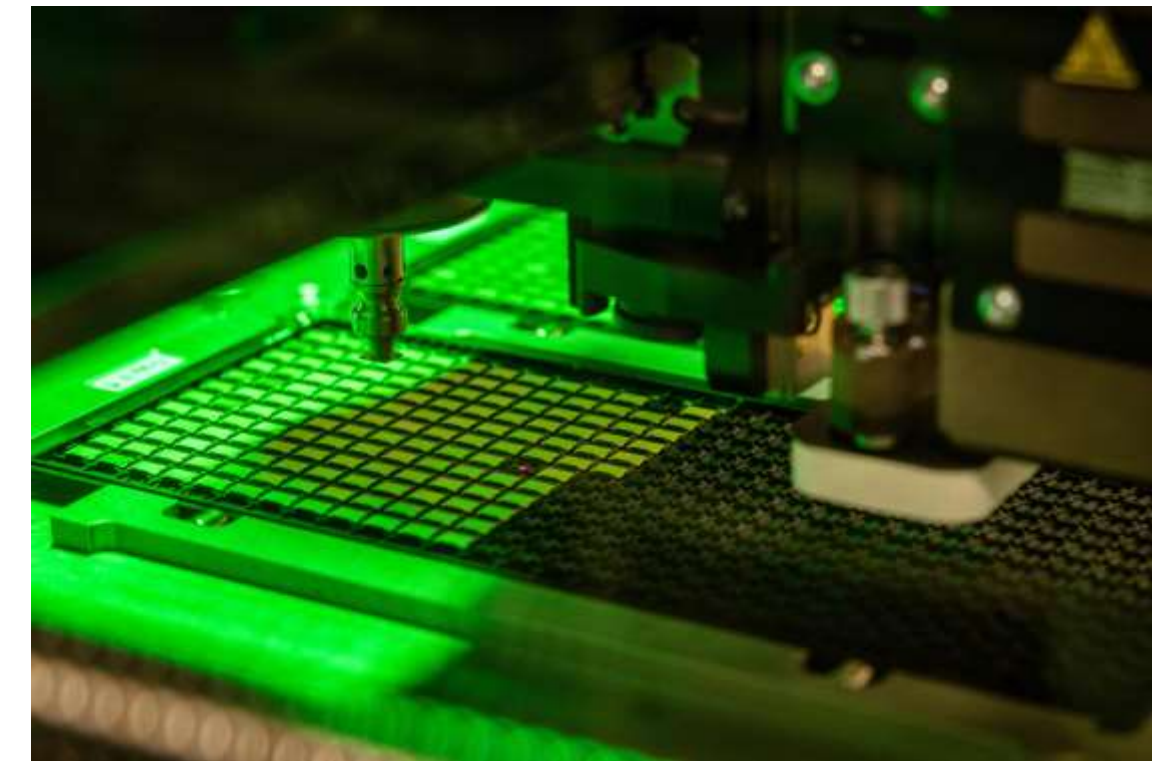


2 Gravity Handler



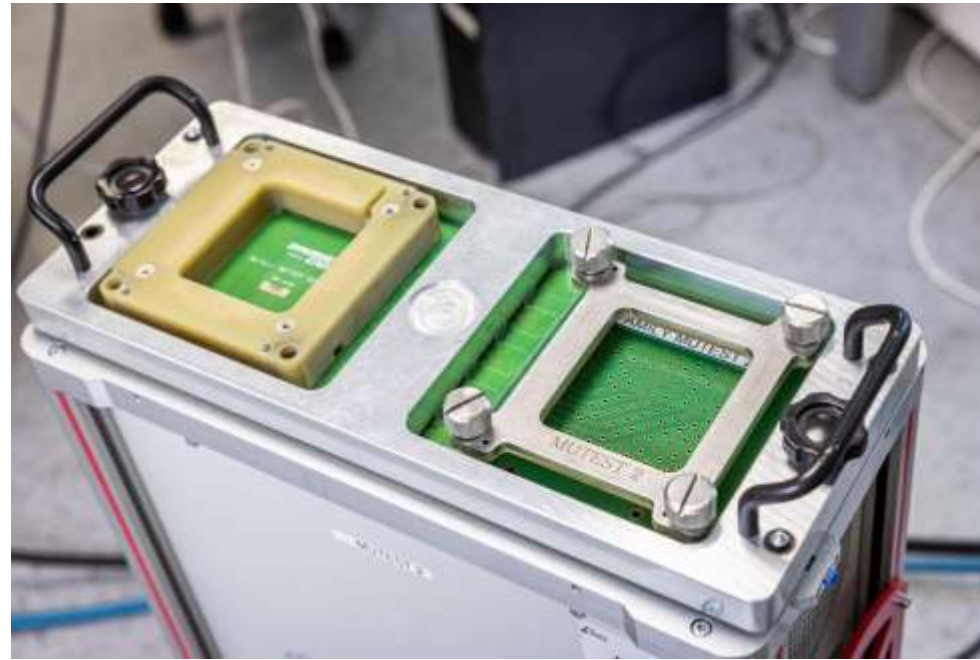
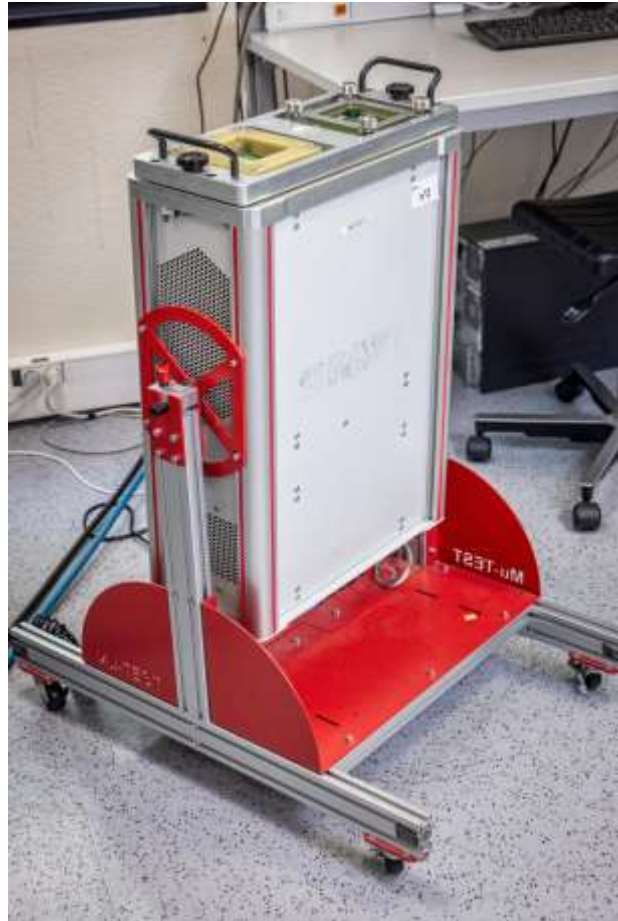
Wafer & Parts Testing

3 Pick & Place Esmo Tallos



Electrical Testers

1 Digital



2 Power



Environmental and Reliability Testing

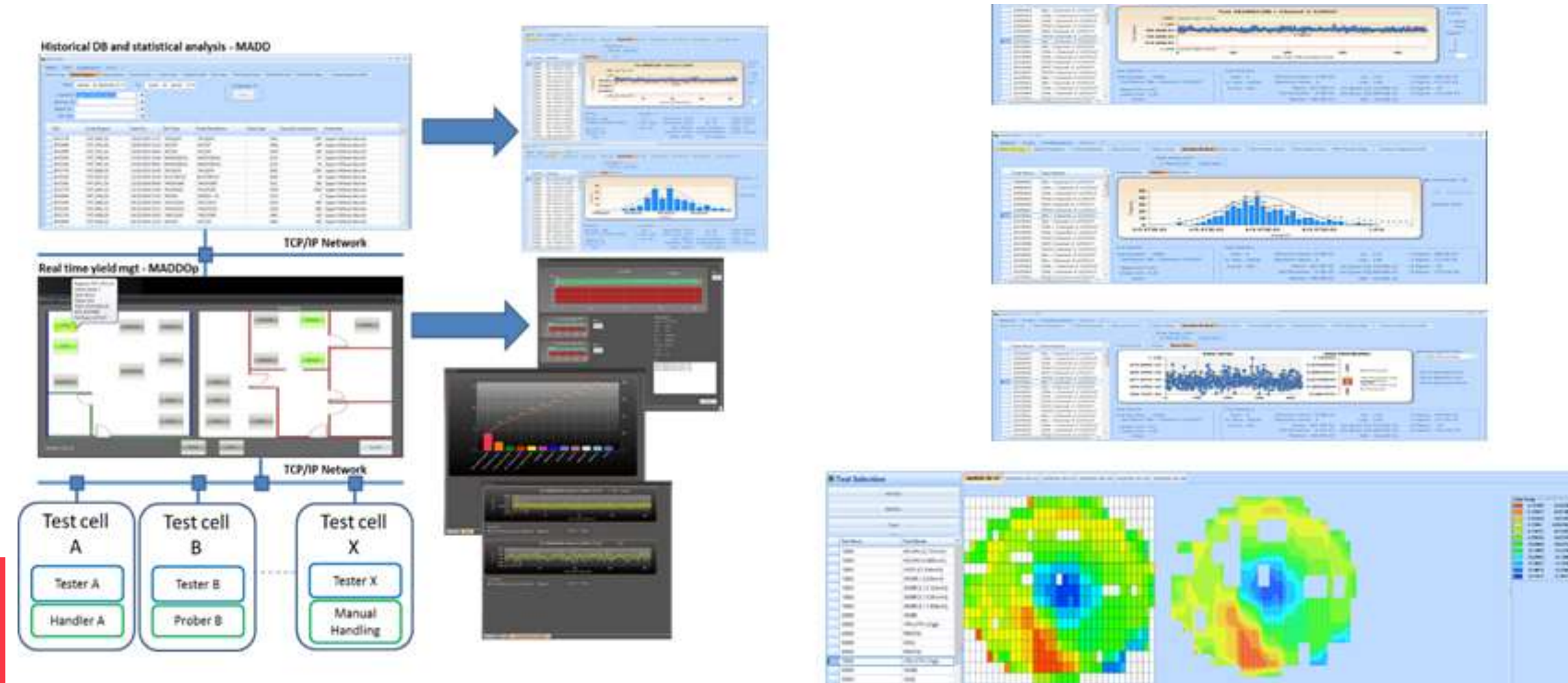
Fully equipped for product qualification to address MIL, ESCC, AEC-101 and JEDEC requirement

- Acceleration
- Autoclave
- Hast
- Damp Heat
- THB
- Burn-in life Test
- Intermittent Operating Life (IOL)
- Vibration (Sinus & Random)
- Mechanical Shock
- Thermal Cycling (+310°C to -185°C with 45°C/min Temperature Ramps)
- Thermal Shock
- Salt Spray
- Thermal Vacuum chambers
 - Temperature Range -55°C up to +125°C
 - Pressure better than 10⁻⁵ mbars
 - In situ test monitoring



Total semiconductor testing

Historical database and Statistical tool analysis



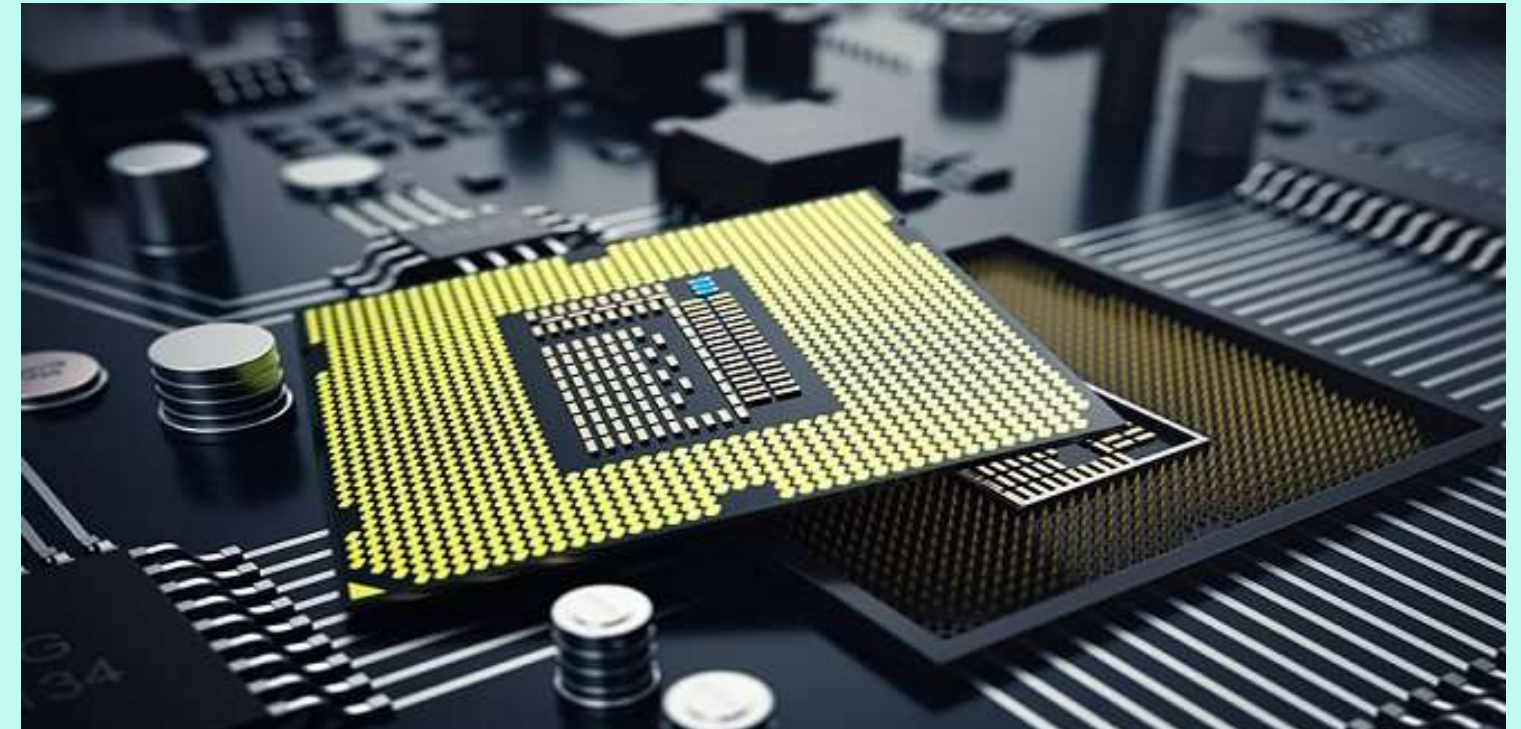
- Test Program qualification
 - GR&R,
 - Precision / Tolerance.
- Per die or device trend plot and distribution analysis.
- Outlier detection based on sigma or Inter quartile computation.
- Tolerance Interval computation for device outside supplier range.
- Multisite testing
- site to site variation checking.
- Wafer map viewer and test analysis.

Packaging & Assembly

Electronic and Optoelectronic Components

Provides contact package design and precision assembly services for a wide range of optoelectronic, microelectronic and MEMS devices.

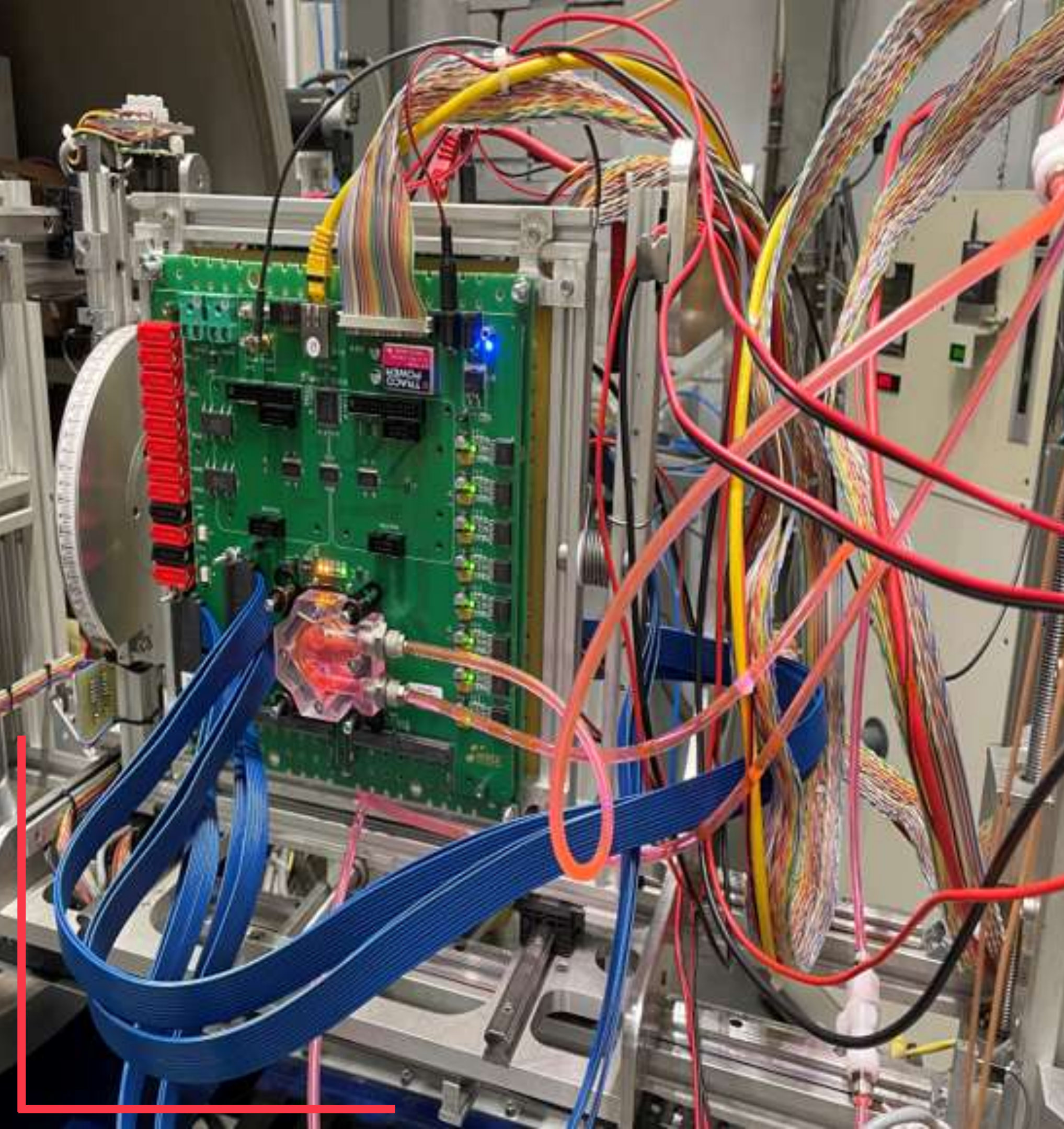
We offer end to end backend semiconductor manufacturing from wafer singulation to assembled product.



- Design for manufacture
- Wafer & die handling
- Die attach
- Wire bonding
- Optical alignment
- Hermetic sealing
- Electrical and optical test
- Fast-Turn, Prototype & Volume manufacturing

ISO 9001:2015 certified manufacturing in accordance with MIL-STD-883 and ESCC standards

ALTER



Radiations services

Engineering radiations involve using standard software tools and in-house software to quickly assess how semiconductor devices behave.

In addition to these activities, ALTER France conducts radiation testing on various semiconductor components, packages, modules and boards.

This testing assesses single event effects, total dose, and displacement damage by exposing them to heavy ions, protons, neutrons, and cobalt 60 irradiation or using laser and XRAY equipment.

ALTER

Radiations services

- Component technology and radiation hardness assessment
- Engineering Radiations Testing & Radiations characterization
- Sourcing & radiation qualification of electronic components
- Part sensitivity evaluation: SEE error
- SEE to COTS (Component Off The Shelves) prediction



Historical activities since 1993 :?

- TID/TNID/SEE tests?
- Thousands of test campaigns successfully conducted since 1993



Radiation engineering? :

- Use of expert radiation simulation tools for shielding analysis
- Internal Simulation software development in partnership with RadConsult



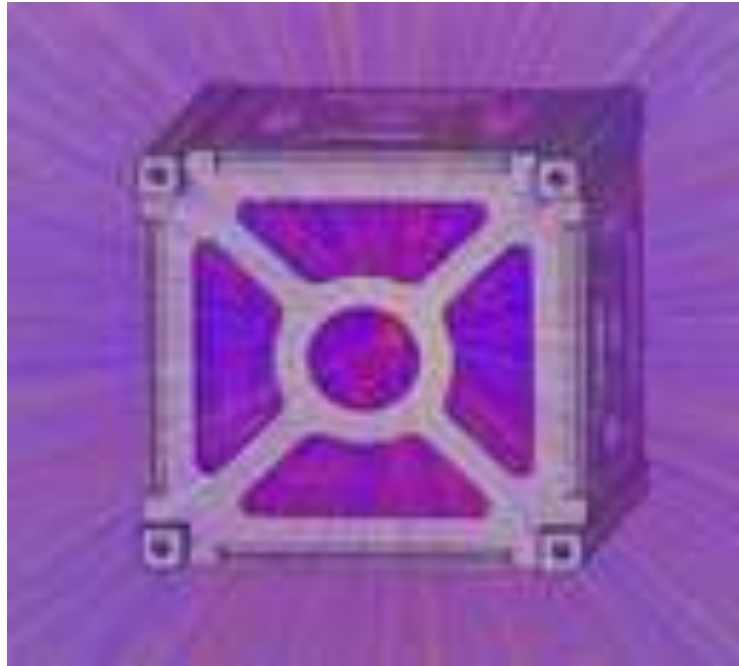
RAD-E4SPACE

ALTER

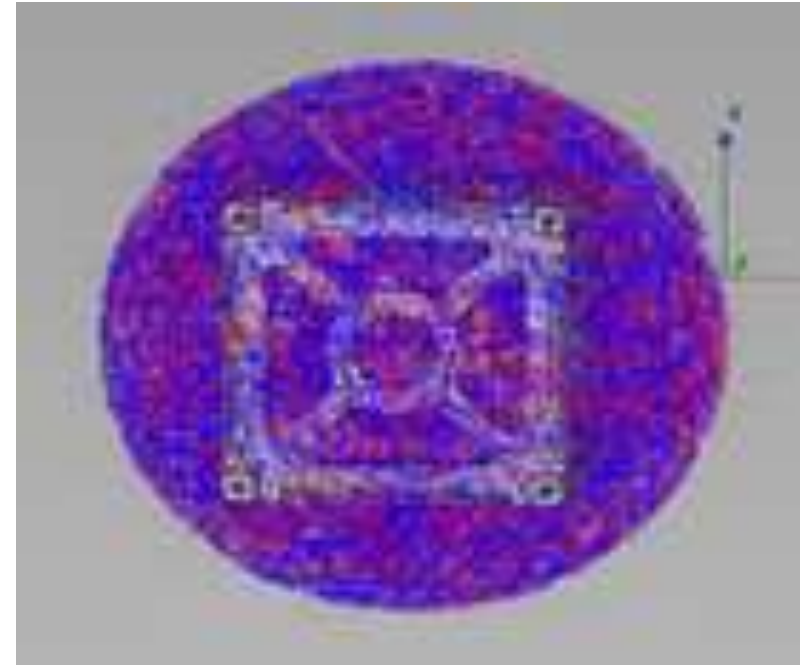
Radiations services



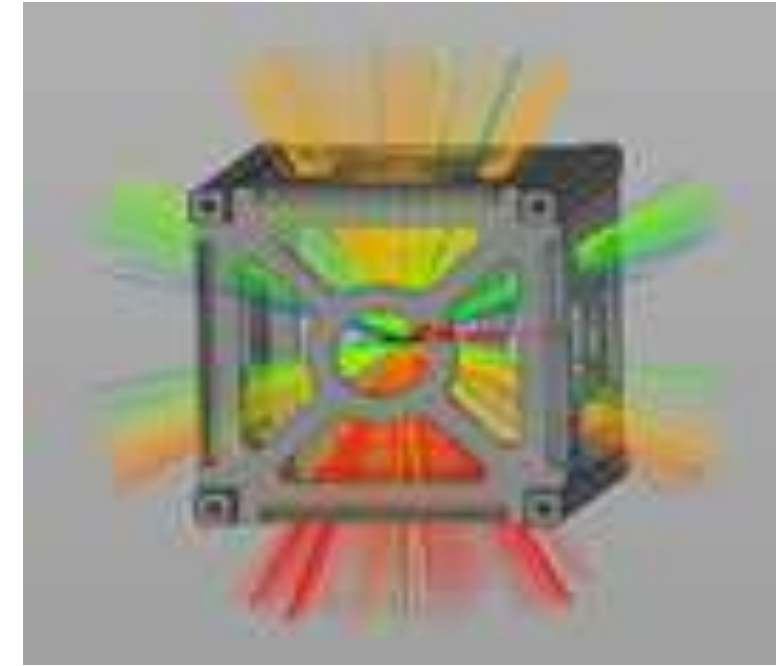
NOVICE & FASTRAD : TID and TNID calculations



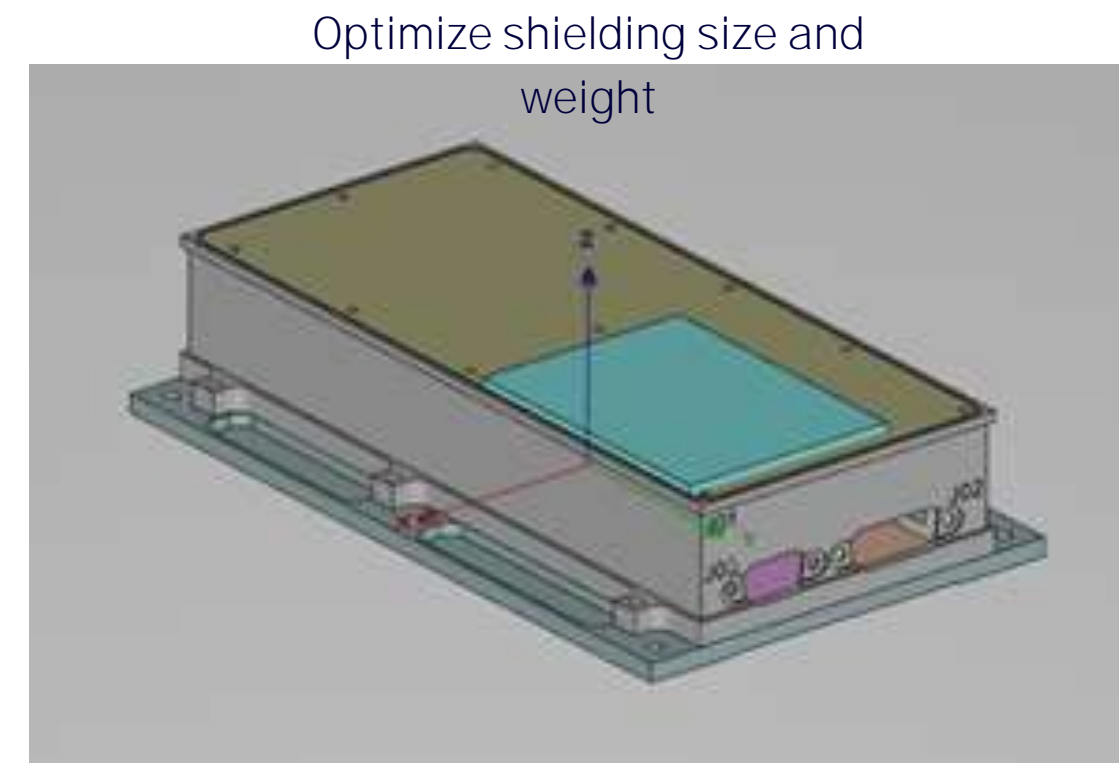
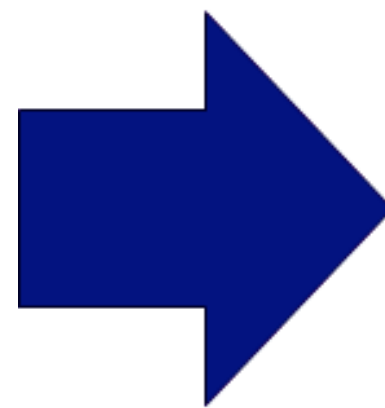
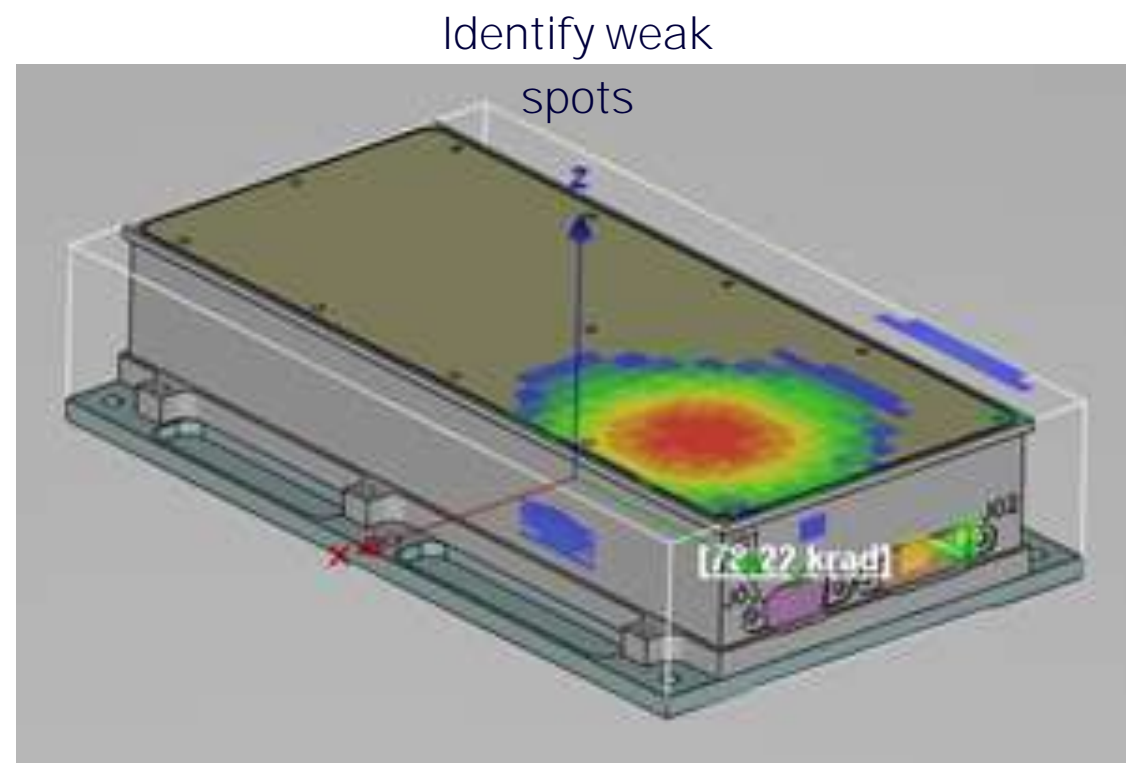
RMC : accurate



FMC : accurate



Ray-tracing : fast

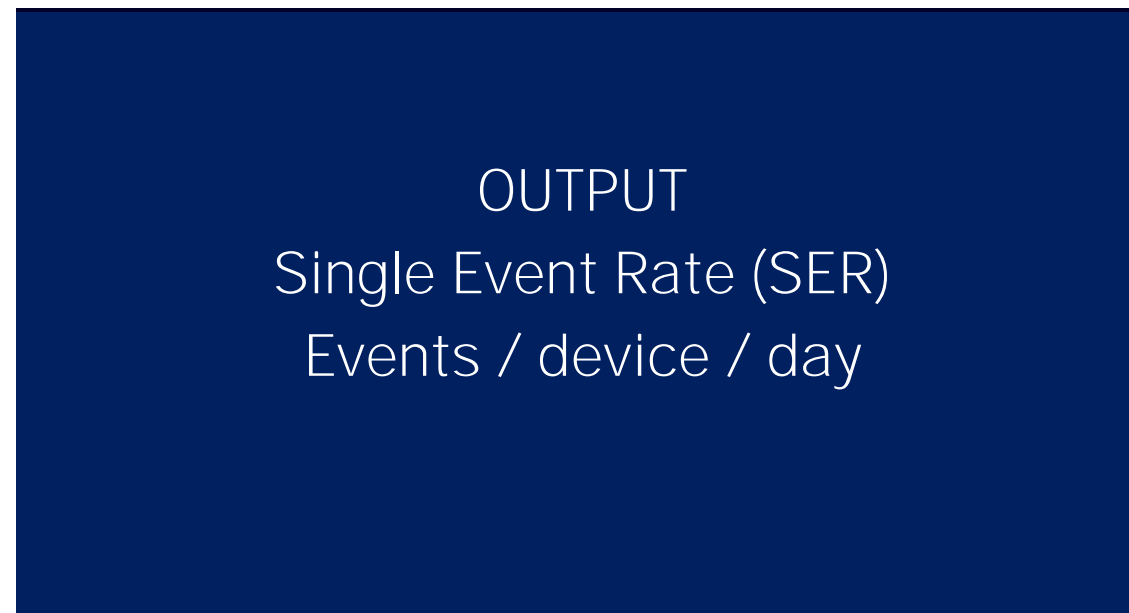


Radiations services

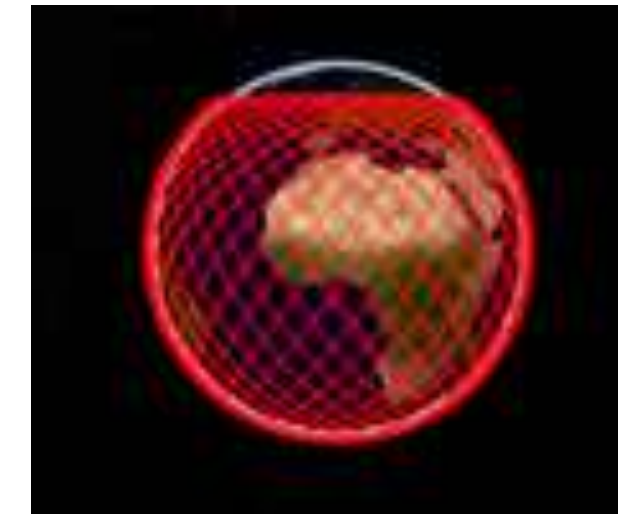
OMERE : Define your environment & In orbit SER

Define the orbit, the duration of the mission and models for:

- Trapped Particles
- Solar Particles
- Galactic Cosmic Rays



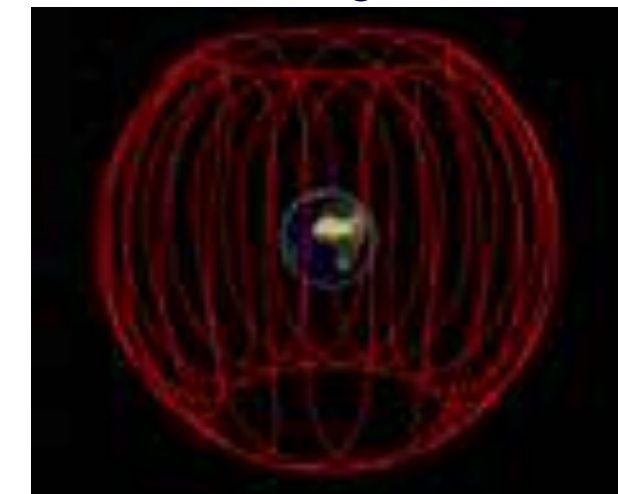
GEO stationary orbit



IS
S



JASON-2



Galileo

Radiations services

ALTER

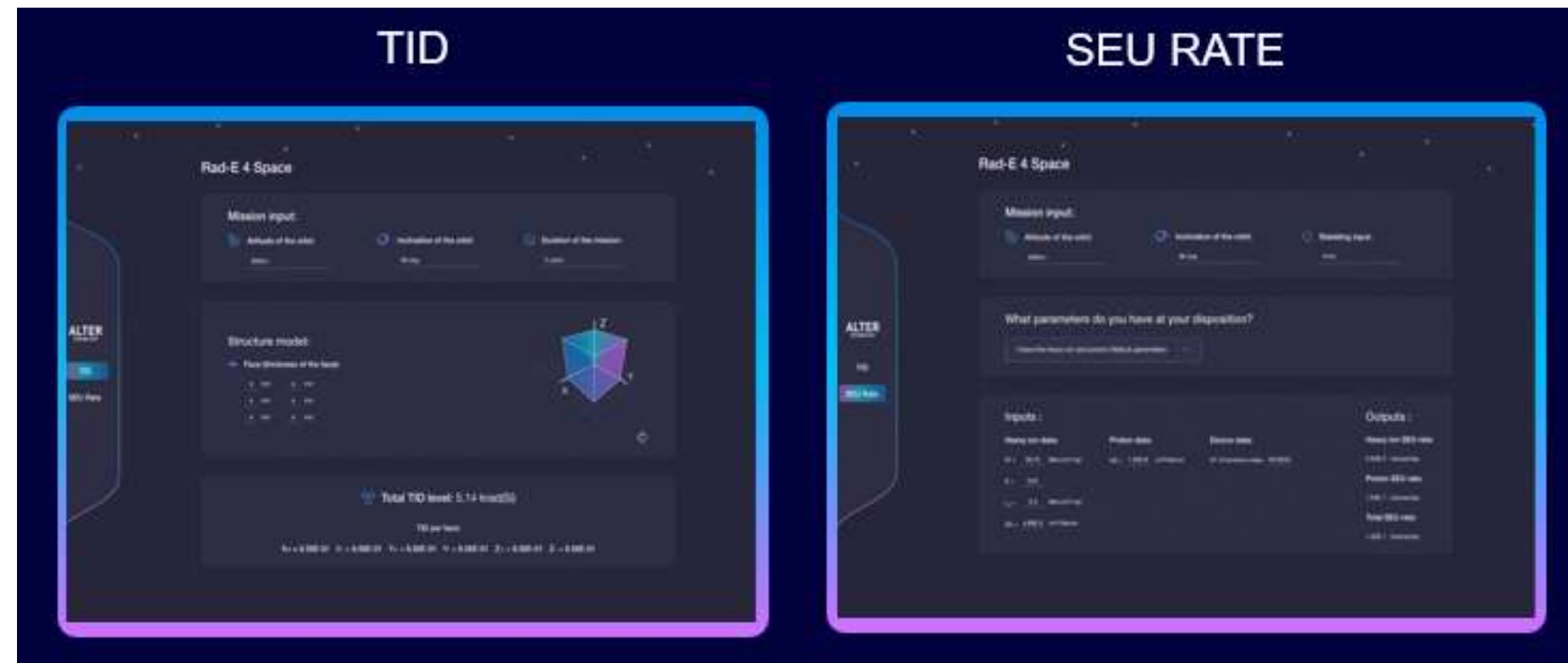
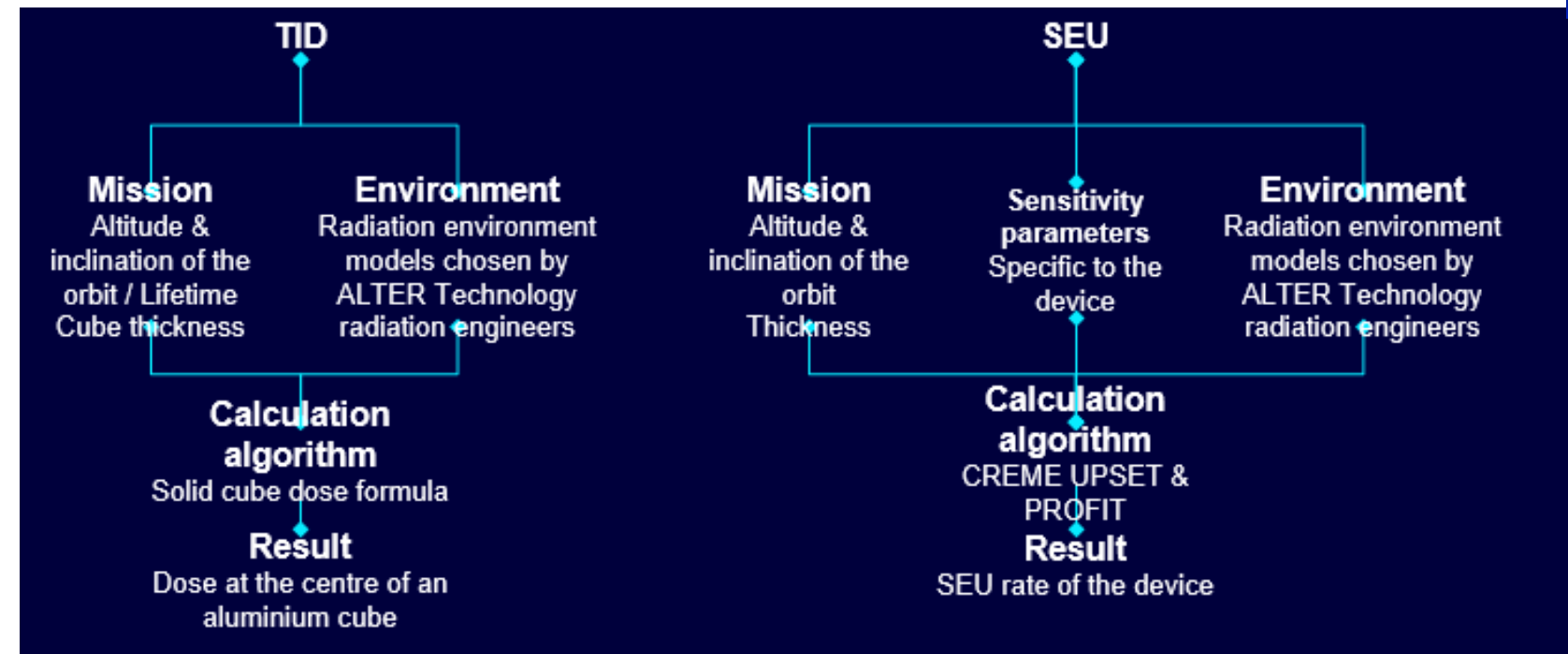


Our tool

Rad-E 4 Space, the first simulation software enabling quick & easy testing for anyone



RAD-E4SPACE

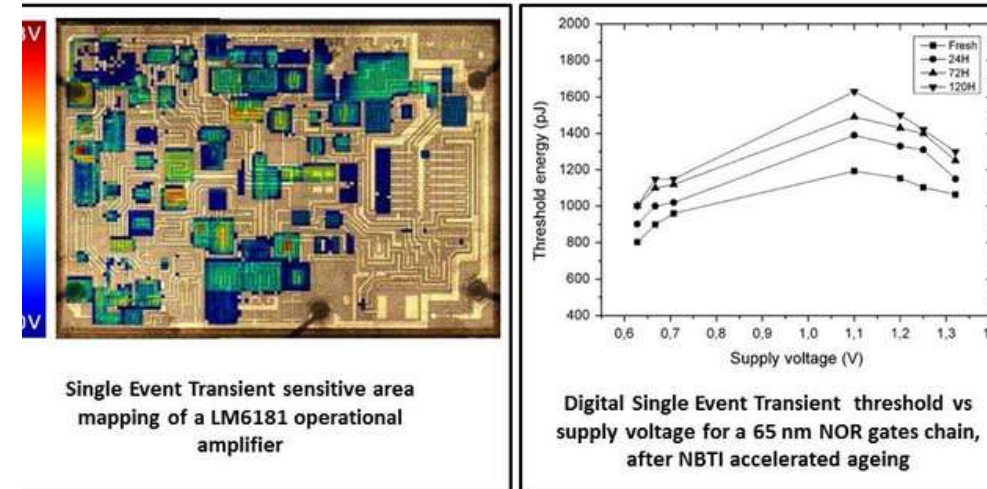
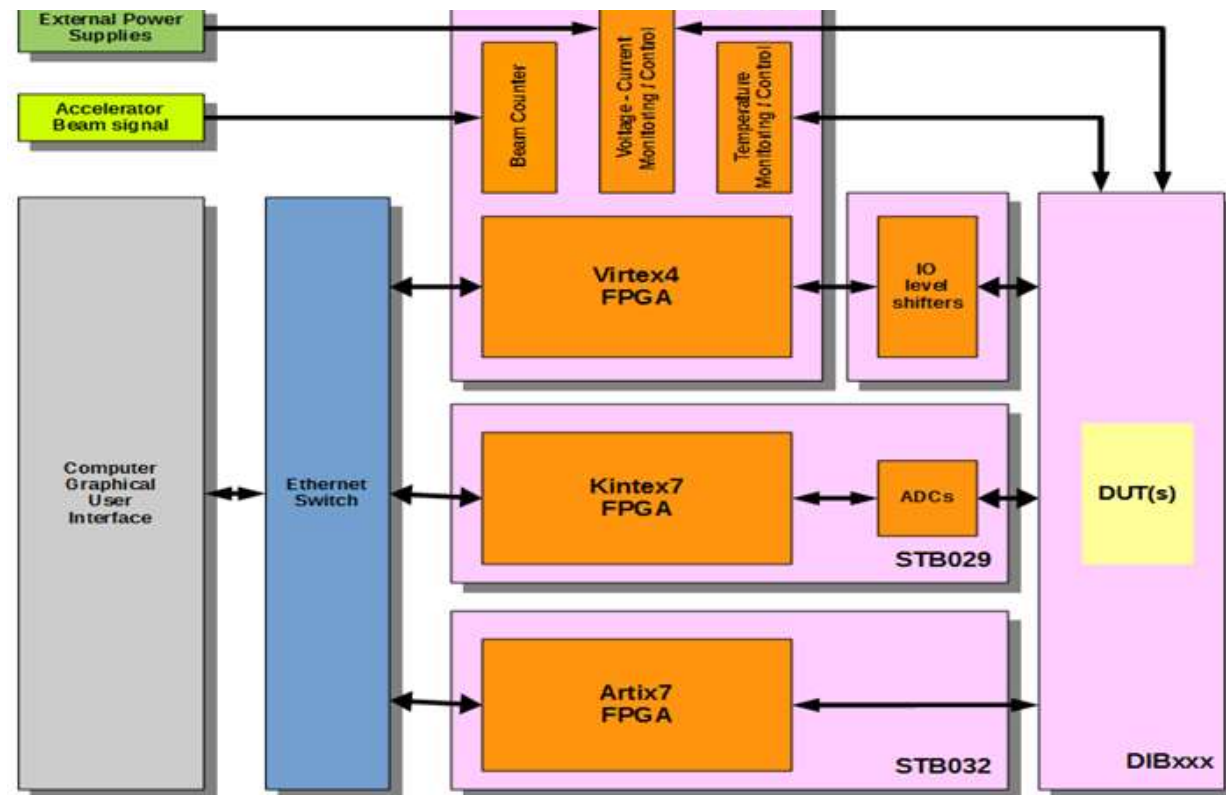


Radiations services



Electronic component testing:

- Test bench development
- Test campaigns (SEE)
- Material testing and component/system radiation characterization



Single Event Effect sensitivity Testing



University of Jyväskylä

UCL

Université catholique de Louvain



TRIUMF



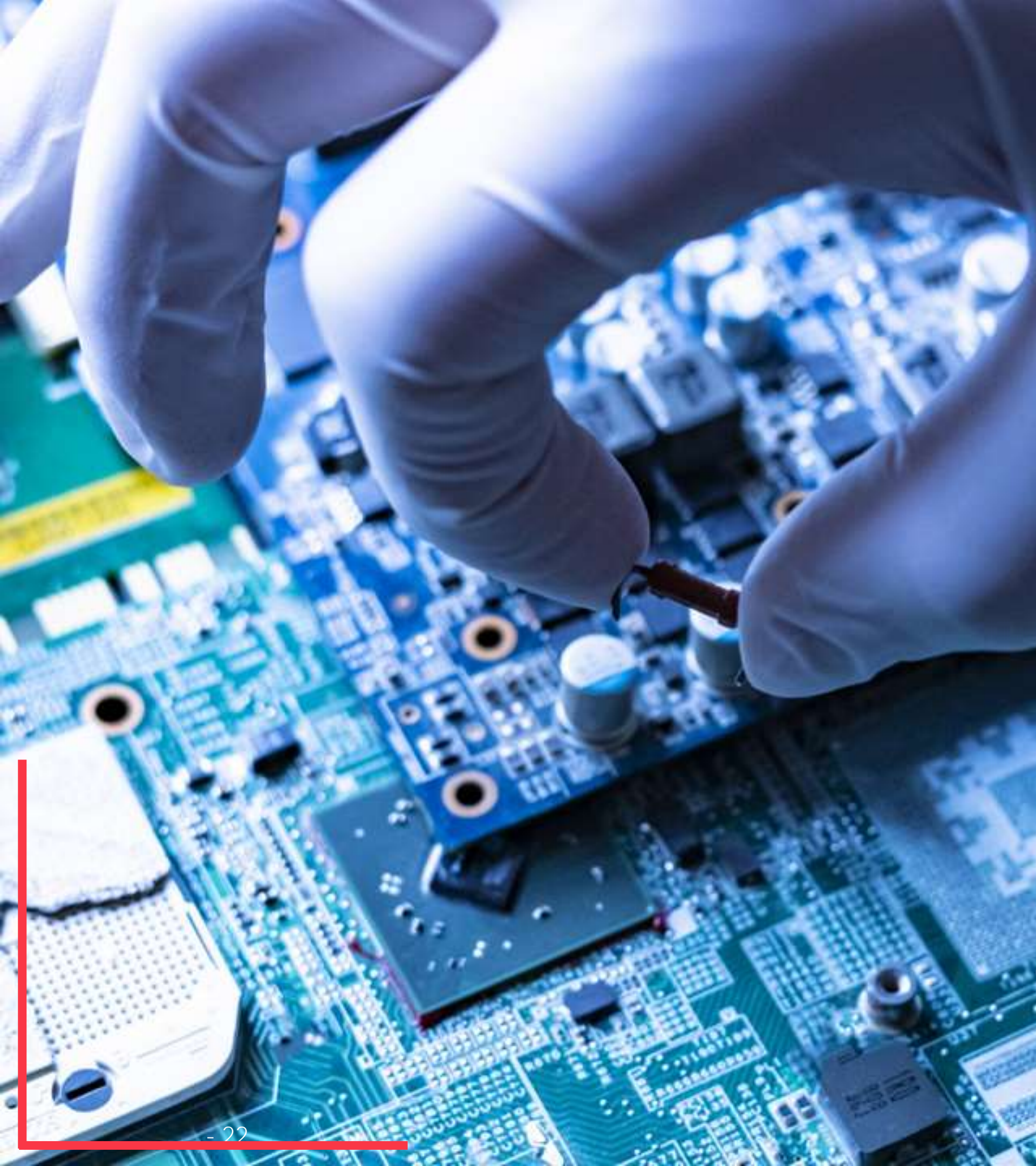
PAUL SCHERRER INSTITUT



Science & Technology Facilities Council
ISIS Neutron and Muon Source



Laboratoire de l'Intégration du Matériau au Système



Procurement

- Ensure compliance with EEE part quality project requirements.
- Align test definitions with project mission.
- Organize meetings with manufacturers to guide design and select mission-compliant part references.
- Manage Outsourced Semiconductor Assembly & Test for obsolete parts and custom devices.
- Issue Part Approval Document (PAD) and procurement specifications.
- Conduct Parts Control Board (PCB) Meetings with end customer participation.
- Organize Equipment Radiation Control Board (ERCB) Meetings with end customer participation.
- Manage and optimize Declared Component List (DCL).
- Review alternatives to meet financial and lead time project requirements.

ALTER

Procurement Service

ALTER Project Name INCOMING INSPECTION
Reference: HX3910.0000 Page: 1/3

This document is customer property that is issued by approval of development, serial priority or complete, without Alter Technology France written authorization.

Part Number : 52000106R Manufacturer : STMicroelectronics
Part Type : 2N2907A Date Code : 21388 Package : LCC-04
Top Marking : Ings 21388 52000106R serial FR
Bottom Marking :
Lot Number : 33821003XP Diffusion Lot Nbr (if applicable):
Received Qty : 25 Procured Qty : 25
Customer : XXXX
Customer PO : XXXXXXXX Item Nbr : XX PO Date : XX/XX/XX
Distributor : Alter Technology Spain Lead finish : Gold
HRN PO Ref. : HRN/CCH/XXXX_XX MSL : N/A
NCR

Procurement Specification : Issue : Rev :
Generic Specification : ESCC 5202 Issue : 10 Rev :
Detail Specification : ESCC 5202001 Issue : 10 Rev :
Spec Amendment : Quality Level : ESCC

Inspection	Date	Accepted Qty	Rejected Qty	Operator
Visual Inspection	XX/XX/XX	25	0	X.XXX
Control of Quantities	XX/XX/XX	25	0	X.XXX
Control of Documentation	XX/XX/XX	1	0	X.XXX
Packaging	XX/XX/XX	25	0	X.XXX

Conditioning : Wafer Pack
Comments :
Diffusion Lot 41240001 / Diffusion Bin VW225NV4 / Wafer 07 / Diffusion Plant SINGAPOUR 6 /
SN 1 lot 26 (total 24)

Documentation Review :
 Data Package

DHU Reference (if applicable): Lot Position: Tests to be performed: Rejected
 Accepted Only use for EQM/EM

<input type="checkbox"/> EDX	<input type="checkbox"/> Visual Inspection	<input type="checkbox"/> Lab Test	<input type="checkbox"/> DPA
<input type="checkbox"/> PND Test	<input type="checkbox"/> Upstreaming	<input type="checkbox"/> RVT	<input type="checkbox"/> Construction Analysis
<input type="checkbox"/> Radiography Test	<input type="checkbox"/> HAST	<input type="checkbox"/> SEI	<input type="checkbox"/> Retesting
<input type="checkbox"/> Humidity Test	<input type="checkbox"/> Thermal Cycling	<input type="checkbox"/> Low Storage Humidity Test	<input type="checkbox"/> Programming

Created by	Name	Function	Date
XXXX	Test Lab Technician		XX/XX/XX
XXXX	Quality Manager		XX/XX/XX

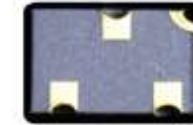
ALTER Project Name INCOMING INSPECTION
Reference: HX3910.0000 Page: 2/3

This document is customer property that is issued by approval of development, serial priority or complete, without Alter Technology France written authorization.

Label Picture:



Package Picture:



ALTER Project Name INCOMING INSPECTION
Reference: HX3910.0000 Page: 3/3

This document is customer property that is issued by approval of development, serial priority or complete, without Alter Technology France written authorization.

Manufacturer COC

Certificate of Conformance

To: ALTERSPAIN
Customer PO: 502032
STMicroelectronics Order Confirmation: 10120040 (ITEM 0000)

Device Type: 2N2907ARUBG Delivered Quantity: 25
Marking: 52000106R FR Date Code: 21388
Diffusion Lot: 41240001 Diffusion Bin: VW225NV4 Wafer: 07

Inspected Certification(s):
Detail Specification: ESCC 5202001 Issue 10
Generic Specification: ESCC 5202 Issue 10
Serial Number: 11036

Remark: Components certified with 99.9999% (24.0000%) of the total lot of body, see conditions for other the generic ESCC qualification data reference, refer to table below.

RVT report reference: RVT00000000

Total Manufactured Quantity: 2774873

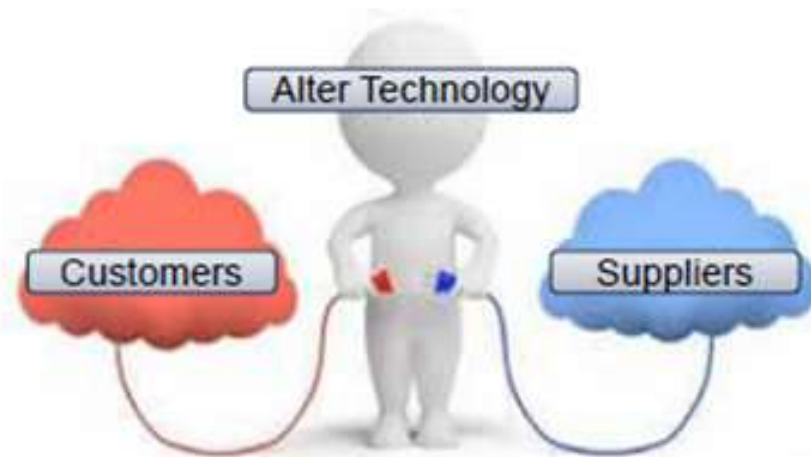
The undersigned certifies that the purchased items have been inspected and the work inspection has shown that each one of them complies with the requirements of the purchase order, and the marking and identification comply with the order.

Date: 03/12/2023 Q.A. Manager: S. PÉREZ Customer Approval: (When required)
Signature: S. Pérez

Doc: Procurement - HiRel - High Rel. parts - Incoming inspection - 1.07 03/12/2023
STMicroelectronics S.A. - 6, rue de l'Industrie - 91000 Evry-Courcouronnes - FRANCE - Page 3 of 3

Part procurement (HiRel and Commercial parts) only through manufacturers or official distributors.

- No specific portfolio allowing to procure all manufacturers
- End User Statement (EUS) management
- To identify procurement requirement (Single Lot Date Code; Date code restriction ...) including precap / Buyoff inspection management
- Non-Conformity Report (NCR) management
- Periodic reporting.



Incoming Inspection

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- Incoming inspection report (documentation checking as CoC, data package, packing label ...). Documents shared through specific cloud (WIMI: access with login and password)
- Specific incoming inspection on request: electrical test, visual inspection with binocular, lead finish analysis
- Destructive Physical Analysis (DPA), Construction Analysis (CA), radiation test (TID, SEE, TNID), upscreening, Lot Acceptance Test (LAT), relifing ...



Storage and Shipment

Parts storage associated with specific software to manage / record traceability, labelling, packing list and storage location:

- Controlled area (temperature and humidity) for hermetic / Hired parts
- Dedicated Long Period storage area (with dry cabinets <5%RH) for plastic package
- Protection against ESD risk during part handling



STORAGE

procurement leadtime securisation with fixed price
(without manufacturer price increase)



- Customized Kitting to optimize your reception
- Shipment with mechanical stress protection
- Dedicated Packing

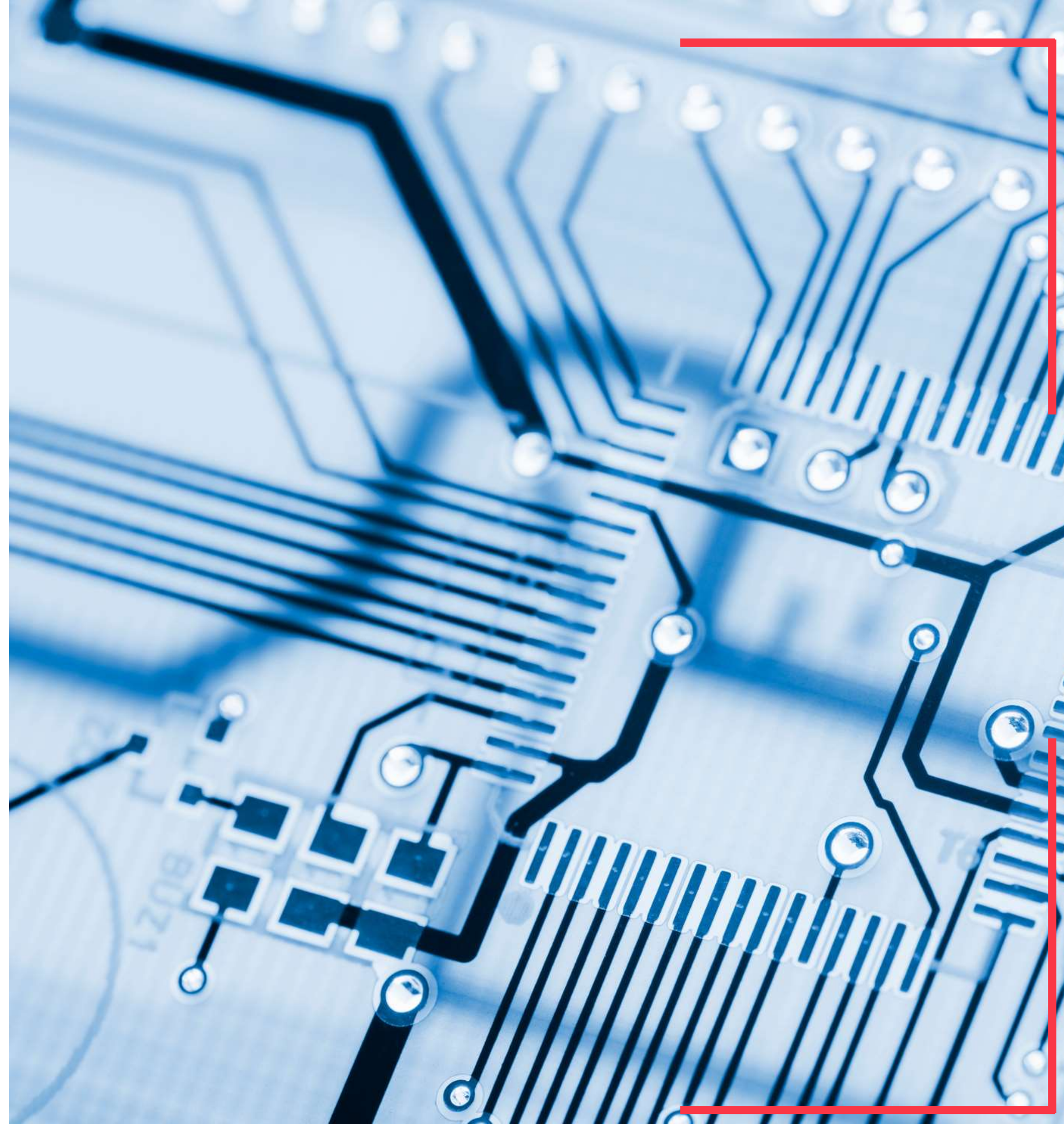


EEE Part Engineering Consulting

Parts procurement through IDM (Integrated Die Manufacturer), distributor partners or in partnership with Alter Technology France group with traceability and testing services added involves the process of sourcing and acquiring semiconductor components for electronic devices while ensuring their authenticity, quality, and performance through traceability and testing.

This comprehensive approach helps mitigate the risks associated with counterfeit or substandard components and ensures that the acquired semiconductors meet the required specifications and standards.

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Thank You

